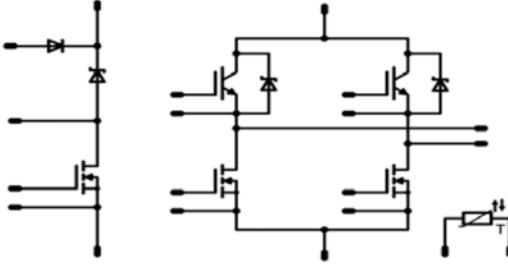


flowSOL 0 BI		600V / 41mOhm
Features	• High efficiency • Ultra fast switching frequency • Low inductive design • SiC in boost	flow0 12mm housing 
Target Applications	• Transformerless solar inverters	
Types	• 10-FZ06BIA041FS01-P898E10	Schematic 

Maximum Ratings

T_j=25°C, unless otherwise specified

Parameter	Symbol	Condition	Value	Unit
Bypass FWD				
Repetitive peak reverse voltage	V _{RRM}		1600	V
Forward current per FWD	I _{FAV}	DC current T _h =80°C T _c =80°C	34 46	A
Surge forward current	I _{FSM}	t _p =10ms T _j =25°C	370	A
I ² t-value	I ² t		370	A ² s
Power dissipation per FWD	P _{tot}	T _j =T _j max T _h =80°C T _c =80°C	39 59	W
Maximum Junction Temperature	T _j max		150	°C

Input Boost MOSFET

Drain to source breakdown voltage	V _{DS}		600	V
DC drain current	I _D	T _j =T _j max T _h =80°C T _c =80°C	32 39	A
Pulsed drain current	I _{Dpulse}	t _p limited by T _j max	272	A
Power dissipation	P _{tot}	T _j =T _j max T _h =80°C T _c =80°C	98 148	W
Gate-source peak voltage	V _{GS}		±20	V
Maximum Junction Temperature	T _j max		150	°C

Maximum Ratings

T_j=25°C, unless otherwise specified

Parameter	Symbol	Condition	Value	Unit
Input Boost FWD				
Peak Repetitive Reverse Voltage	V _{RRM}	T _j =25°C	600	V
DC forward current	I _F	T _j =T _j max T _h =80°C T _c =80°C	24 31	A
Repetitive peak forward current	I _{FRM}	t _p limited by T _j max	171	A
Power dissipation	P _{tot}	T _j =T _j max T _h =80°C T _c =80°C	49 74	W
Maximum Junction Temperature	T _j max		175	°C
Buck FWD				
Peak Repetitive Reverse Voltage	V _{RRM}	T _j =25°C	600	V
DC forward current	I _F	T _j =T _j max T _h =80°C T _c =80°C	28 38	A
Repetitive peak forward current	I _{FRM}	t _p limited by T _j max	30	A
Power dissipation per FWD	P _{tot}	T _j =T _j max T _h =80°C T _c =80°C	45 68	W
Maximum Junction Temperature	T _j max		150	°C
Buck MOSFET				
Drain to source breakdown voltage	V _{DS}		600	V
DC drain current	I _D	T _j =T _j max T _h =80°C T _c =80°C	32 39	A
Pulsed drain current	I _{Dpulse}	t _p limited by T _j max	272	A
Power dissipation	P _{tot}	T _j =T _j max T _h =80°C T _c =80°C	98 148	W
Gate-source peak voltage	V _{gs}		±20	V
Maximum Junction Temperature	T _j max		150	°C
Polarity Switch IGBT				
Collector-emitter break down voltage	V _{CE}		600	V
DC collector current	I _C	T _j =T _j max T _h =80°C T _c =80°C	45 45	A
Repetitive peak collector current	I _{Cpuls}	t _p limited by T _j max	150	A
Power dissipation per IGBT	P _{tot}	T _j =T _j max T _h =80°C T _c =80°C	84 128	W
Gate-emitter peak voltage	V _{GE}		±20	V
Short circuit ratings	t _{sc} V _{CC}	T _j ≤150°C V _{GE} =15V	6 360	μs V
Maximum Junction Temperature	T _j max		175	°C

Maximum Ratings

T_j=25°C, unless otherwise specified

Parameter	Symbol	Condition	Value	Unit
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Thermal Properties

Storage temperature	T _{stg}		-40...+125	°C
Operation temperature under switching condition	T _{op}		-40...+(T _{jmax} - 25)	°C

Insulation Properties

Insulation voltage	V _{is}	t=2s	DC voltage	4000	V
Creepage distance				min 12,7	mm
Clearance				min 12,7	mm

Characteristic Values

Parameter	Symbol	Conditions					Value			Unit	
			V_{GE} [V] or V_{GS} [V]	V_r [V] or V_{CE} [V] or V_{DS} [V]	I_c [A] or I_F [A] or I_D [A]	T_J	Min	Typ	Max		
Bypass FWD											
Forward voltage	solar inverter				35	$T_J=25^\circ C$ $T_J=125^\circ C$	0,7	1,18 1,15	1,3	V	
Threshold voltage (for power loss calc. only)	V_{to}				35	$T_J=25^\circ C$ $T_J=125^\circ C$		0,89 0,79		V	
Slope resistance (for power loss calc. only)	r_t				35	$T_J=25^\circ C$ $T_J=125^\circ C$		0,01 0,01		Ω	
Reverse current	I_r			1600		$T_J=25^\circ C$ $T_J=125^\circ C$			0,15	mA	
Thermal resistance chip to heatsink per chip	R_{thJH}	Thermal foil thickness=76um Kunze foil KU- ALF5						1,80		K/W	
Thermal resistance chip to case per chip	R_{thJC}										
Input Boost MOSFET											
Static drain to source ON resistance	$R_{DS(on)}$		10		44	$T_J=25^\circ C$ $T_J=125^\circ C$		0,043 0,086		Ω	
Gate threshold voltage	$V_{(GS)th}$	$V_{GS}=V_{DS}$			0,00296	$T_J=25^\circ C$ $T_J=125^\circ C$	2,4	3	3,6	V	
Gate to Source Leakage Current	I_{gss}		20	0		$T_J=25^\circ C$ $T_J=125^\circ C$			100	nA	
Zero Gate Voltage Drain Current	I_{dss}		0	400		$T_J=25^\circ C$ $T_J=125^\circ C$			5000	nA	
Turn On Delay Time	$t_{d(ON)}$	R _{goff} =8 Ω R _{gon} =8 Ω	10	400	15	$T_J=25^\circ C$ $T_J=125^\circ C$		34 33		ns	
Rise Time	t_r					$T_J=25^\circ C$ $T_J=125^\circ C$		8 10			
Turn off delay time	$t_{d(OFF)}$					$T_J=25^\circ C$ $T_J=125^\circ C$		276 300			
Fall time	t_f					$T_J=25^\circ C$ $T_J=125^\circ C$		87 93			
Turn-on energy loss per pulse	E_{on}					$T_J=25^\circ C$ $T_J=125^\circ C$		0,20 0,15		mWs	
Turn-off energy loss per pulse	E_{off}					$T_J=25^\circ C$ $T_J=125^\circ C$		0,06 0,07			
Total gate charge	Q_g					$T_J=25^\circ C$ $T_J=125^\circ C$		290		nC	
Gate to source charge	Q_{gs}	f=1MHz	0/10	480	44	$T_J=25^\circ C$ $T_J=125^\circ C$		36			
Gate to drain charge	Q_{gd}					$T_J=25^\circ C$ $T_J=125^\circ C$		150			
Input capacitance	C_{iss}							6530		pF	
Output capacitance	C_{oss}		0	100		$T_J=25^\circ C$		360			
Reverse transfer capacitance	C_{rss}							tbd.			
Thermal resistance chip to heatsink per chip	R_{thJH}	Thermal foil thickness=76um Kunze foil KU- ALF5						0,72		K/W	
Thermal resistance chip to case per chip	R_{thJC}							0,47			
Input Boost FWD											
Forward voltage	V_F				24	$T_J=25^\circ C$ $T_J=150^\circ C$	1	1,56 1,82	1,9	V	
Reverse leakage current	I_{rm}		10	400	15	$T_J=25^\circ C$ $T_J=150^\circ C$			150	μA	
Peak recovery current	I_{RRM}	R _{gon} =8 Ω	10	400	15	$T_J=25^\circ C$ $T_J=150^\circ C$		18 8		A	
Reverse recovery time	t_{rr}					$T_J=25^\circ C$ $T_J=150^\circ C$		15 14		ns	
Reverse recovery charge	Q_{rr}					$T_J=25^\circ C$ $T_J=150^\circ C$		0,24 0,13		μC	
Reverse recovered energy	E_{rec}					$T_J=25^\circ C$ $T_J=150^\circ C$		0,04 0,03		mWs	
Peak rate of fall of recovery current	$d(i_{rec})/dt$					$T_J=25^\circ C$ $T_J=150^\circ C$		4809 1562		$A/\mu s$	
Thermal resistance chip to heatsink per chip	R_{thJH}	Thermal foil thickness=76um Kunze foil KU- ALF5						1,95		K/W	
Thermal resistance chip to case per chip	R_{thJC}							1,28			

Characteristic Values

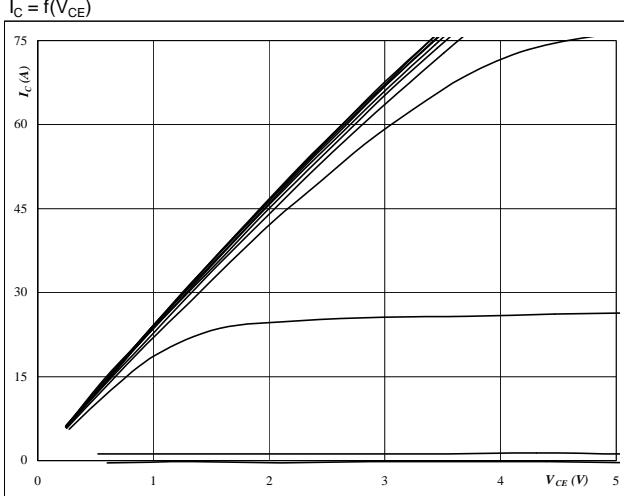
Parameter	Symbol	Conditions				Value			Unit
		V_{GE} [V] or V_{GS} [V]	V_T [V] or V_{CE} [V] or V_{DS} [V]	I_C [A] or I_F [A] or I_D [A]	T_J	Min	Typ	Max	
Buck FWD									
FWD forward voltage	V_F			30	$T_J=25^\circ C$ $T_J=125^\circ C$	1,5	2,58 1,80	2,8	V
Peak reverse recovery current	I_{RRM}	$R_{gon}=8 \Omega$	10 400	15	$T_J=25^\circ C$ $T_J=125^\circ C$	10 29			A
Reverse recovery time	t_{rr}				$T_J=25^\circ C$ $T_J=125^\circ C$		11 38		ns
Reverse recovered charge	Q_{rr}				$T_J=25^\circ C$ $T_J=125^\circ C$	0,12 0,62			μC
Peak rate of fall of recovery current	$di(rec)_{max}/dt$				$T_J=25^\circ C$ $T_J=125^\circ C$		2478 1706		$A/\mu s$
Reverse recovered energy	E_{rec}				$T_J=25^\circ C$ $T_J=125^\circ C$	0,03 0,08			mWs
Thermal resistance chip to heatsink per chip	R_{thJH}				1,57			K/W	
Thermal resistance chip to case per chip	R_{thJC}				1,03				
Buck MOSFET									
Static drain to source ON resistance	$R_{ds(on)}$		10		44	$T_J=25^\circ C$ $T_J=125^\circ C$		43 86	
Gate threshold voltage	$V_{(GS)th}$			$V_{DS}=V_{GS}$	0,00296	$T_J=25^\circ C$ $T_J=125^\circ C$	2,4	3	3,6
Gate to Source Leakage Current	I_{gss}		20	0		$T_J=25^\circ C$ $T_J=125^\circ C$			100
Zero Gate Voltage Drain Current	I_{dss}		0	400		$T_J=25^\circ C$ $T_J=125^\circ C$			5000
Turn On Delay Time	$t_{d(ON)}$	$R_{goFF}=8 \Omega$ $R_{gon}=8 \Omega$	10 400	15		$T_J=25^\circ C$ $T_J=125^\circ C$	34 33		ns
Rise Time	t_r					$T_J=25^\circ C$ $T_J=125^\circ C$		9 9,4	
Turn off delay time	$t_{d(OFF)}$					$T_J=25^\circ C$ $T_J=125^\circ C$	275 302		
Fall time	t_f					$T_J=25^\circ C$ $T_J=125^\circ C$		139,2 4,5	
Turn-on energy loss per pulse	E_{on}					$T_J=25^\circ C$ $T_J=125^\circ C$	0,138 0,355		mWs
Turn-off energy loss per pulse	E_{off}					$T_J=25^\circ C$ $T_J=125^\circ C$		0,055 0,075	
Total gate charge	Q_g		0/10	480	44	$T_J=25^\circ C$	290 36 150		nC
Gate to source charge	Q_{gs}								
Gate to drain charge	Q_{gd}								
Input capacitance	C_{iss}	$f=1MHz$	0	100		$T_J=25^\circ C$	6530 360 tbd.		pF
Output capacitance	C_{oss}								
Reverse transfer capacitance	C_{rss}								
Thermal resistance chip to heatsink per chip	R_{thJH}	$Thermal\ foil\ thickness=76\mu m$ $Kunze\ foil\ KU-ALF5$					0,72 0,47		K/W
Thermal resistance chip to case per chip	R_{thJC}								

Characteristic Values

Parameter	Symbol	Conditions				Value			Unit	
		V_{GE} [V] or V_{GS} [V]	V_r [V] or V_{CE} [V] or V_{DS} [V]	I_c [A] or I_F [A] or I_D [A]	T_j	Min	Typ	Max		
Polarity Switch IGBT										
Gate-emitter threshold voltage	$V_{GE(th)}$	$V_{CE}=V_{GE}$			0,00043	$T_j=25^\circ\text{C}$ $T_j=150^\circ\text{C}$	5	5,8	6,5	V
Collector-emitter saturation voltage	$V_{CE(sat)}$		15		50	$T_j=25^\circ\text{C}$ $T_j=150^\circ\text{C}$	1	1,58 1,78	2,05	V
Collector-emitter cut-off incl FWD	I_{CES}		0	600		$T_j=25^\circ\text{C}$ $T_j=150^\circ\text{C}$			0,2	mA
Gate-emitter leakage current	I_{GES}		20	0		$T_j=25^\circ\text{C}$ $T_j=150^\circ\text{C}$			650	nA
Integrated Gate resistor	R_{gint}							none		Ω
Turn-on delay time	$t_{d(on)}$	$R_{goff}=8\ \Omega$ $R_{gon}=8\ \Omega$				$T_j=25^\circ\text{C}$ $T_j=150^\circ\text{C}$		na. na.		ns
Rise time	t_r					$T_j=25^\circ\text{C}$ $T_j=150^\circ\text{C}$		na. na.		
Turn-off delay time	$t_{d(off)}$					$T_j=25^\circ\text{C}$ $T_j=150^\circ\text{C}$		na. na.		
Fall time	t_f					$T_j=25^\circ\text{C}$ $T_j=150^\circ\text{C}$		na. na.		
Turn-on energy loss per pulse	E_{on}					$T_j=25^\circ\text{C}$ $T_j=150^\circ\text{C}$		na. na.		mWs
Turn-off energy loss per pulse	E_{off}					$T_j=25^\circ\text{C}$ $T_j=150^\circ\text{C}$		na. na.		
Input capacitance	C_{ies}	$f=1\text{MHz}$				$T_j=25^\circ\text{C}$		3140		pF
Output capacitance	C_{oss}		0	25				200		
Reverse transfer capacitance	C_{rss}							93		
Gate charge	Q_{Gate}		15	480	50	$T_j=25^\circ\text{C}$		310		nC
Thermal resistance chip to heatsink per chip	R_{thJH}	Thermal grease thickness $\leq 50\mu\text{m}$ $\lambda = 1\ \text{W/mK}$				$T_j=25^\circ\text{C}$		1,13		K/W
Thermal resistance chip to case per chip	R_{thJC}							0,74		
Thermistor										
Rated resistance*	R_{25}					$T_j=25^\circ\text{C}$	17,5	22	29	k Ω
Deviation of R100	$D_{R/R}$	$R100=1503\Omega$				$T_c=100^\circ\text{C}$				%/K
Power dissipation	P					$T_j=25^\circ\text{C}$		210		mW
B-value	$B_{(25/100)}$	Tol. $\pm 3\%$				$T_j=25^\circ\text{C}$		4000		K

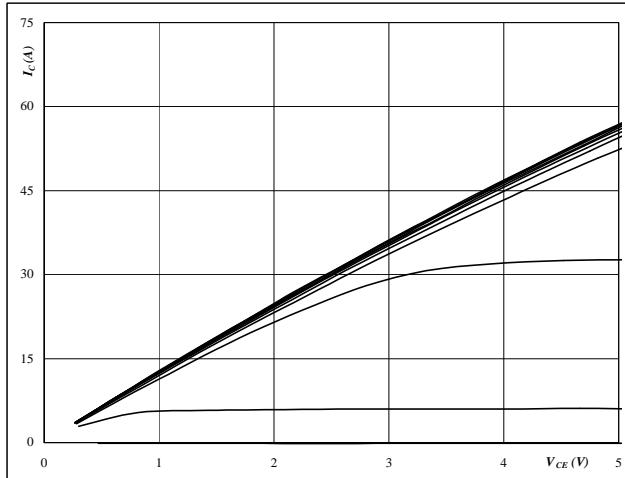
Buck

Figure 1
Typical output characteristics
 $I_C = f(V_{CE})$



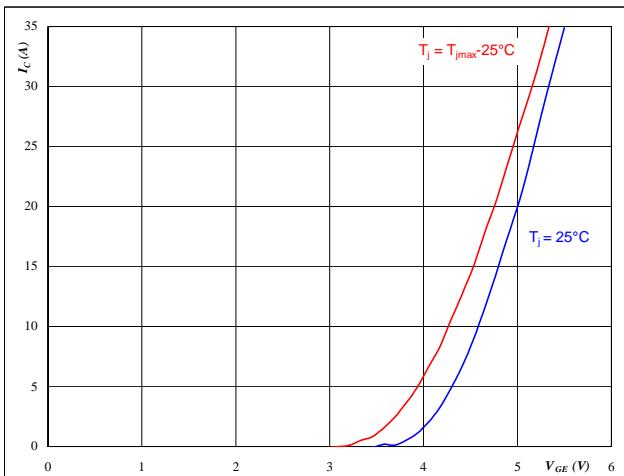
At
 $t_p = 250 \mu s$
 $T_j = 25 {}^\circ C$
 V_{GE} from 3 V to 13 V in steps of 1 V

Figure 2
Typical output characteristics
 $I_C = f(V_{CE})$



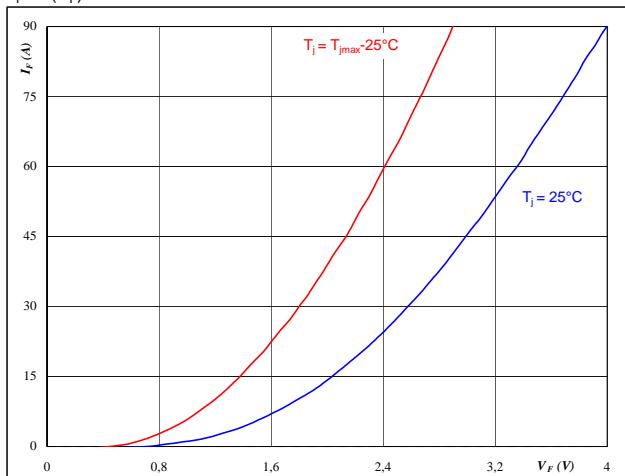
At
 $t_p = 250 \mu s$
 $T_j = 125 {}^\circ C$
 V_{GE} from 3 V to 13 V in steps of 1 V

Figure 3
Typical transfer characteristics
 $I_C = f(V_{GE})$



At
 $t_p = 250 \mu s$
 $V_{CE} = 10 V$

Figure 4
Typical diode forward current as a function of forward voltage
 $I_F = f(V_F)$



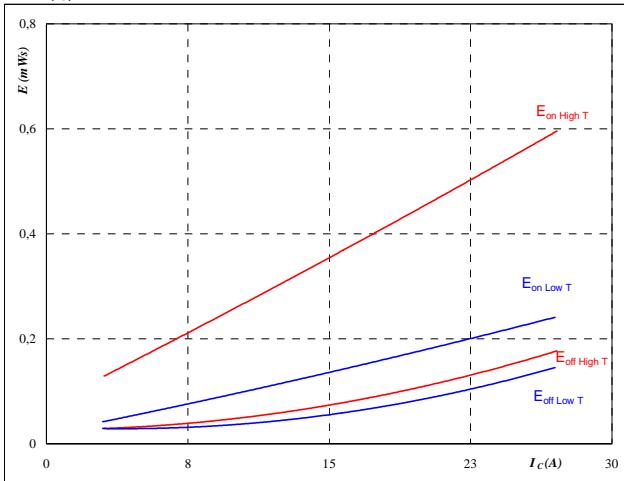
At
 $t_p = 250 \mu s$

Buck

Figure 5

**Typical switching energy losses
as a function of collector current**

$$E = f(I_C)$$



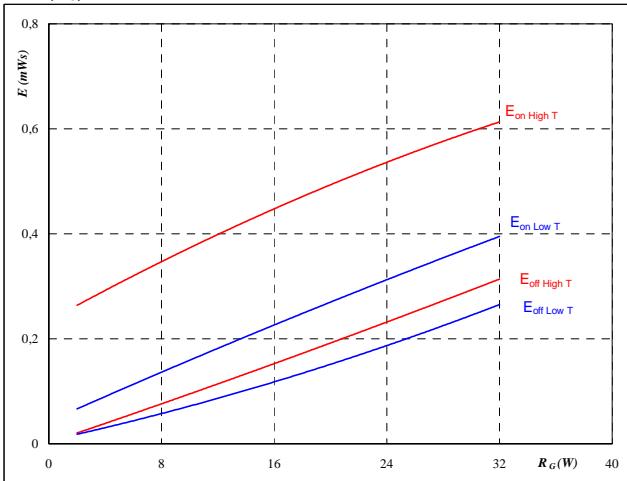
With an inductive load at

$$\begin{aligned} T_j &= 25/125 \quad ^\circ\text{C} \\ V_{CE} &= 400 \quad \text{V} \\ V_{GE} &= 10 \quad \text{V} \\ R_{gon} &= 8 \quad \Omega \\ R_{goff} &= 8 \quad \Omega \end{aligned}$$

MOSFET**Figure 6**

**Typical switching energy losses
as a function of gate resistor**

$$E = f(R_G)$$



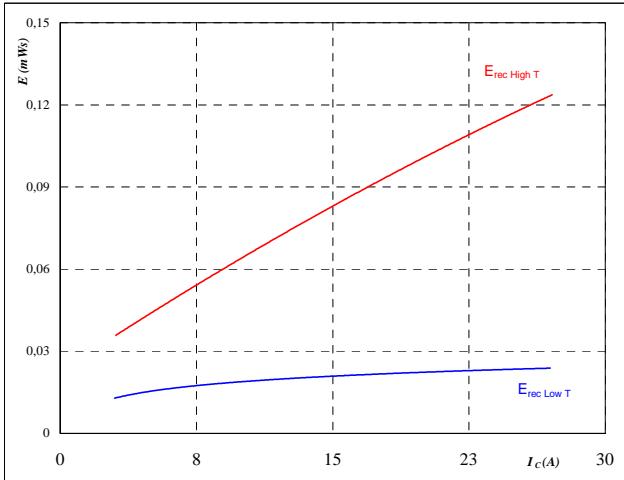
With an inductive load at

$$\begin{aligned} T_j &= 25/125 \quad ^\circ\text{C} \\ V_{CE} &= 400 \quad \text{V} \\ V_{GE} &= 10 \quad \text{V} \\ I_C &= 15 \quad \text{A} \end{aligned}$$

Figure 7

**Typical reverse recovery energy loss
as a function of collector current**

$$E_{rec} = f(I_C)$$



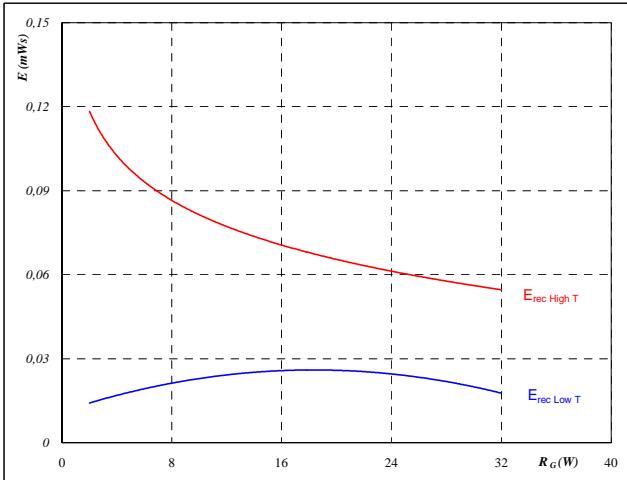
With an inductive load at

$$\begin{aligned} T_j &= 25/125 \quad ^\circ\text{C} \\ V_{CE} &= 400 \quad \text{V} \\ V_{GE} &= 10 \quad \text{V} \\ R_{gon} &= 8 \quad \Omega \end{aligned}$$

FWD**Figure 8**

**Typical reverse recovery energy loss
as a function of gate resistor**

$$E_{rec} = f(R_G)$$



With an inductive load at

$$\begin{aligned} T_j &= 25/125 \quad ^\circ\text{C} \\ V_{CE} &= 400 \quad \text{V} \\ V_{GE} &= 10 \quad \text{V} \\ I_C &= 15 \quad \text{A} \end{aligned}$$

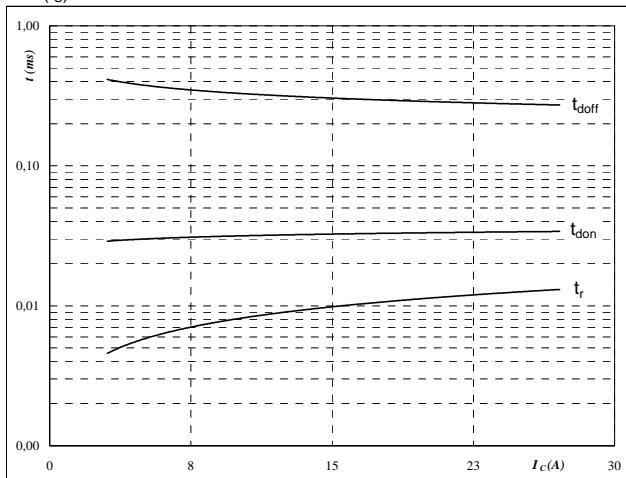
Buck

Figure 9

MOSFET

Typical switching times as a function of collector current

$t = f(I_C)$



With an inductive load at

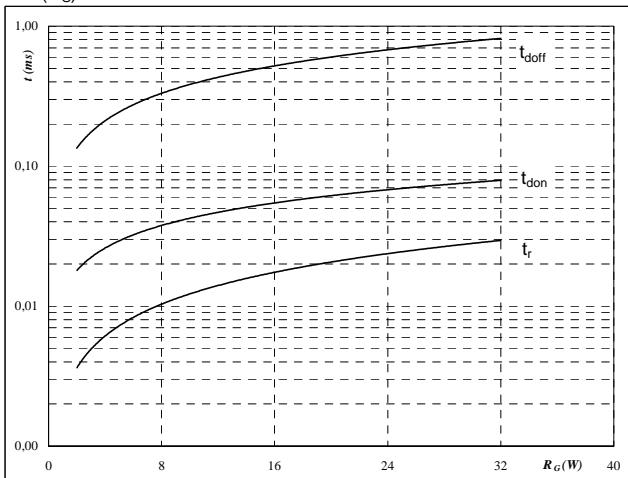
$$\begin{aligned} T_j &= 125 \quad ^\circ\text{C} \\ V_{CE} &= 400 \quad \text{V} \\ V_{GE} &= 10 \quad \text{V} \\ R_{gon} &= 8 \quad \Omega \\ R_{goff} &= 8 \quad \Omega \end{aligned}$$

Figure 10

MOSFET

Typical switching times as a function of gate resistor

$t = f(R_G)$



With an inductive load at

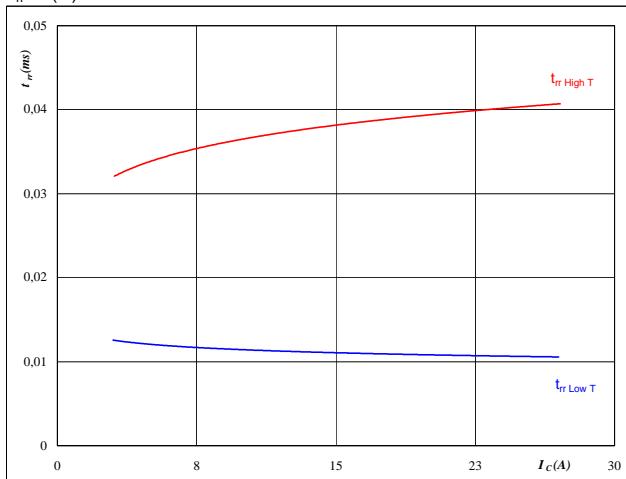
$$\begin{aligned} T_j &= 125 \quad ^\circ\text{C} \\ V_{CE} &= 400 \quad \text{V} \\ V_{GE} &= 10 \quad \text{V} \\ I_C &= 15 \quad \text{A} \end{aligned}$$

Figure 11

FWD

Typical reverse recovery time as a function of collector current

$t_{rr} = f(I_C)$



At

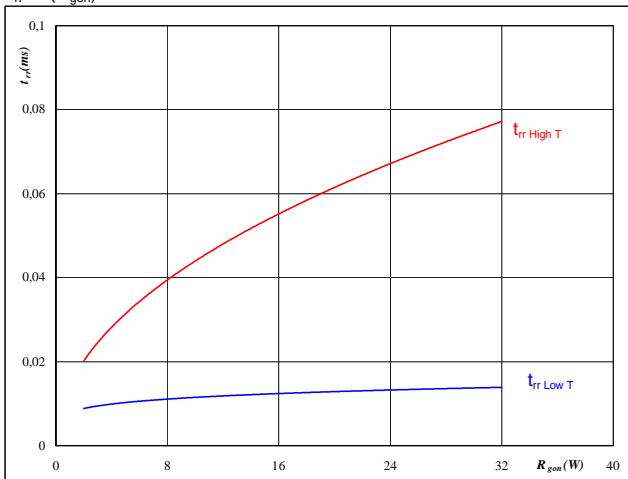
$$\begin{aligned} T_j &= 25/125 \quad ^\circ\text{C} \\ V_{CE} &= 400 \quad \text{V} \\ V_{GE} &= 10 \quad \text{V} \\ R_{gon} &= 8 \quad \Omega \end{aligned}$$

Figure 12

FWD

Typical reverse recovery time as a function of IGBT turn on gate resistor

$t_{rr} = f(R_{gon})$



At

$$\begin{aligned} T_j &= 25/125 \quad ^\circ\text{C} \\ V_R &= 400 \quad \text{V} \\ I_F &= 15 \quad \text{A} \\ V_{GE} &= 10 \quad \text{V} \end{aligned}$$

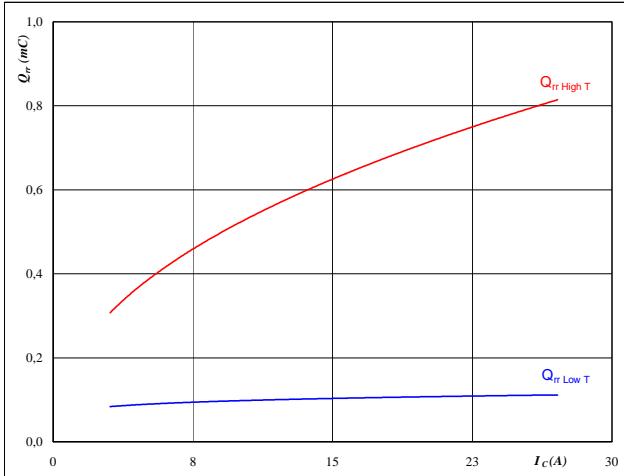
Buck

Figure 13

FWD

Typical reverse recovery charge as a function of collector current

$$Q_{rr} = f(I_C)$$

**At**

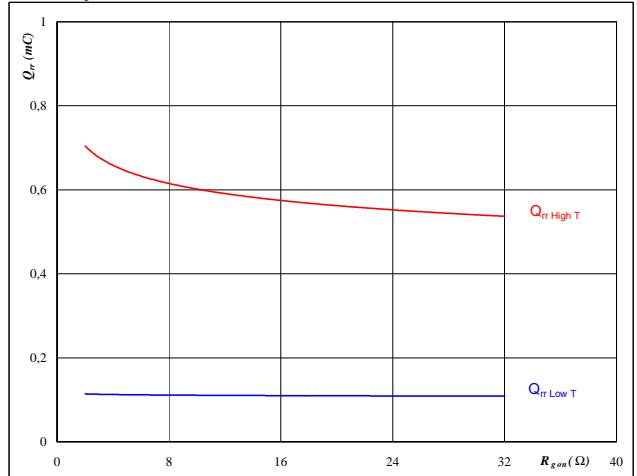
$$\begin{aligned} T_j &= 25/125 \quad ^\circ\text{C} \\ V_{CE} &= 400 \quad \text{V} \\ V_{GE} &= 10 \quad \text{V} \\ R_{gon} &= 8 \quad \Omega \end{aligned}$$

Figure 14

FWD

Typical reverse recovery charge as a function of IGBT turn on gate resistor

$$Q_{rr} = f(R_{gon})$$

**At**

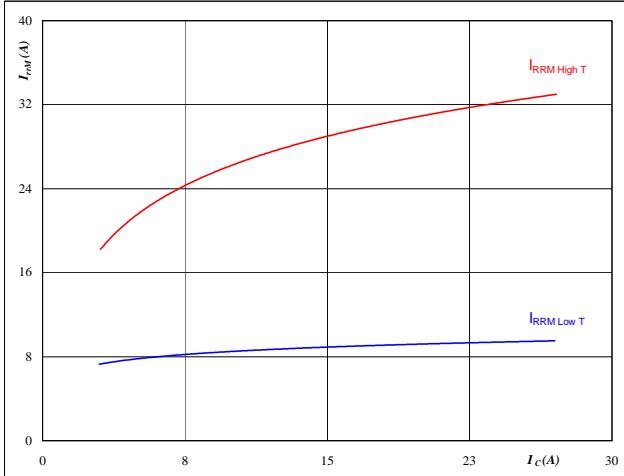
$$\begin{aligned} T_j &= 25/125 \quad ^\circ\text{C} \\ V_R &= 400 \quad \text{V} \\ I_F &= 15 \quad \text{A} \\ V_{GE} &= 10 \quad \text{V} \end{aligned}$$

Figure 15

FWD

Typical reverse recovery current as a function of collector current

$$I_{RRM} = f(I_C)$$

**At**

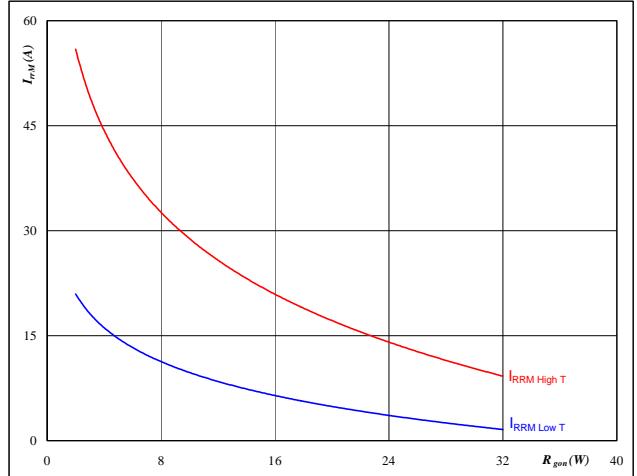
$$\begin{aligned} T_j &= 25/125 \quad ^\circ\text{C} \\ V_{CE} &= 400 \quad \text{V} \\ V_{GE} &= 10 \quad \text{V} \\ R_{gon} &= 8 \quad \Omega \end{aligned}$$

Figure 16

FWD

Typical reverse recovery current as a function of IGBT turn on gate resistor

$$I_{RRM} = f(R_{gon})$$

**At**

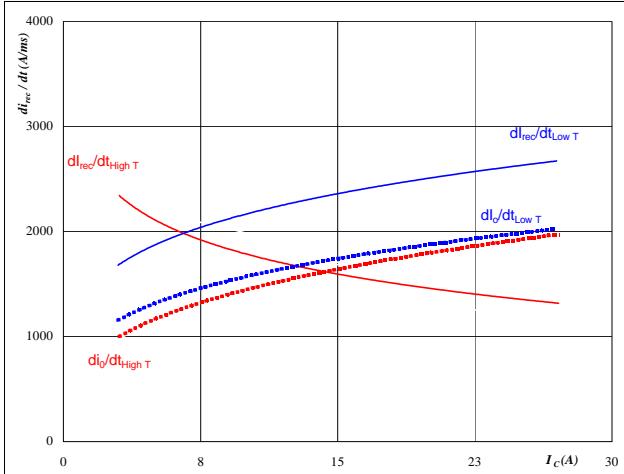
$$\begin{aligned} T_j &= 25/125 \quad ^\circ\text{C} \\ V_R &= 400 \quad \text{V} \\ I_F &= 15 \quad \text{A} \\ V_{GE} &= 10 \quad \text{V} \end{aligned}$$

Buck

Figure 17

FWD

Typical rate of fall of forward
and reverse recovery current as a
function of collector current
 $dl_0/dt, dl_{rec}/dt = f(I_c)$

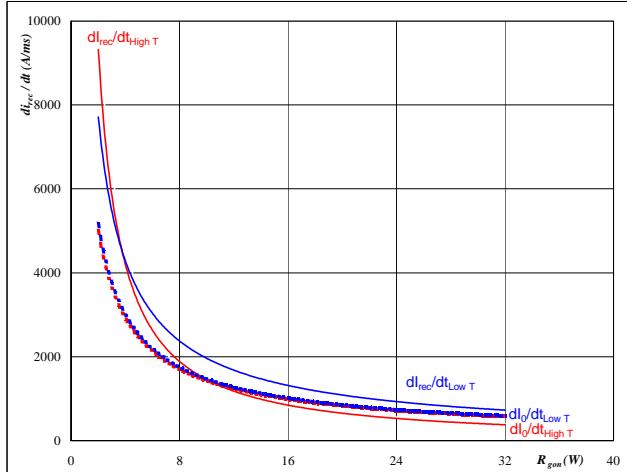
**At**

$T_j = 25/125 \text{ } ^\circ\text{C}$
 $V_{CE} = 400 \text{ V}$
 $V_{GE} = 10 \text{ V}$
 $R_{gon} = 8 \Omega$

Figure 18

FWD

Typical rate of fall of forward
and reverse recovery current as a
function of IGBT turn on gate resistor
 $dl_0/dt, dl_{rec}/dt = f(R_{gon})$

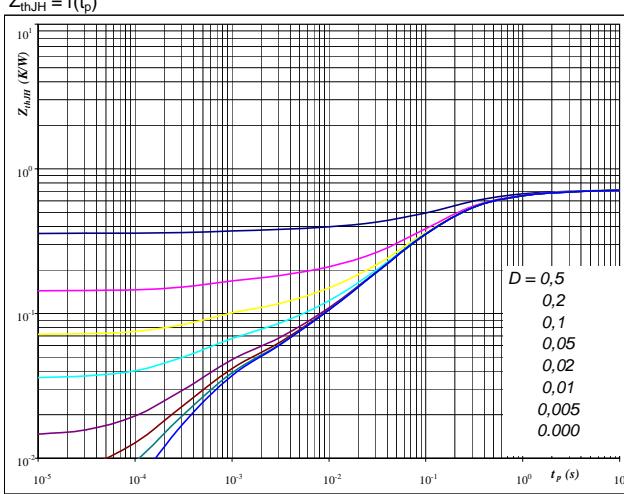
**At**

$T_j = 25/125 \text{ } ^\circ\text{C}$
 $V_R = 400 \text{ V}$
 $I_F = 15 \text{ A}$
 $V_{GE} = 10 \text{ V}$

Figure 19

MOSFET

IGBT transient thermal impedance
as a function of pulse width
 $Z_{thJH} = f(t_p)$

**At**

$D = t_p / T$
 $R_{thJH} = 0,72 \text{ K/W}$

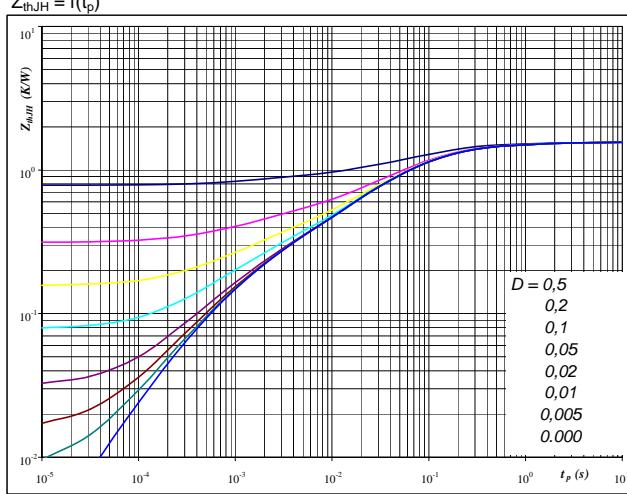
IGBT thermal model values

R (C/W)	Tau (s)
0,02	8,7E+00
0,10	1,3E+00
0,37	2,0E-01
0,15	6,0E-02
0,04	8,2E-03
0,03	5,7E-04

Figure 20

FWD

FWD transient thermal impedance
as a function of pulse width
 $Z_{thJH} = f(t_p)$

**At**

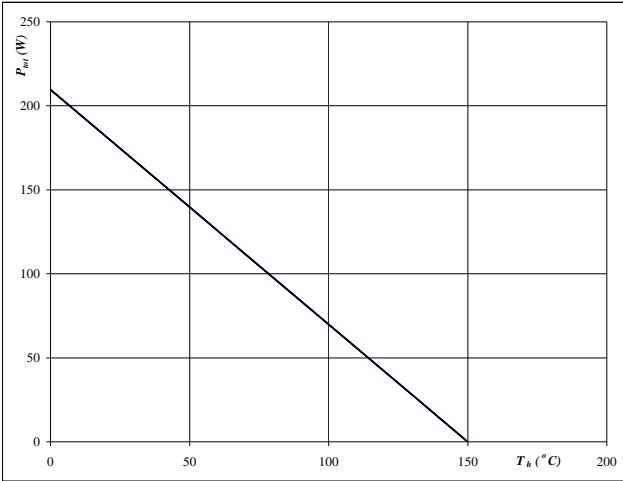
$D = t_p / T$
 $R_{thJH} = 1,57 \text{ K/W}$

FWD thermal model values

R (C/W)	Tau (s)
0,06	3,6E+00
0,18	4,9E-01
0,76	8,0E-02
0,35	1,6E-02
0,16	1,9E-03
0,06	3,9E-04

Buck

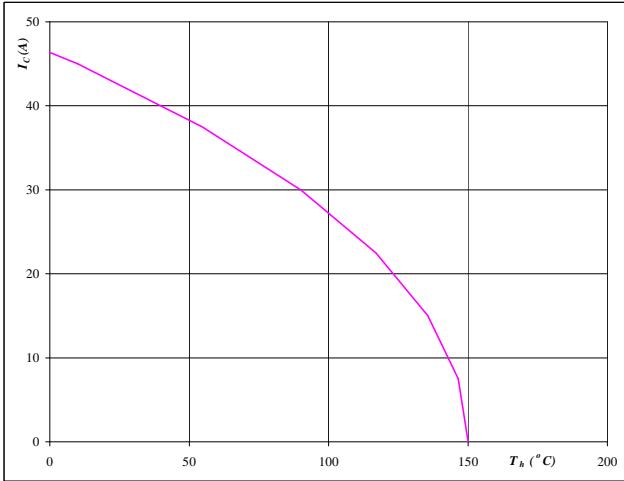
Figure 21
Power dissipation as a function of heatsink temperature
 $P_{\text{tot}} = f(T_h)$



At
 $T_j = 150$ °C

MOSFET

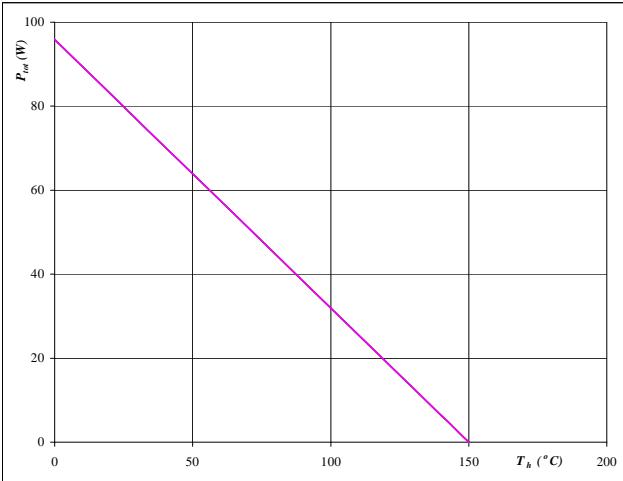
Figure 22
Collector current as a function of heatsink temperature
 $I_C = f(T_h)$



At
 $T_j = 150$ °C
 $V_{GE} = 10$ V

MOSFET

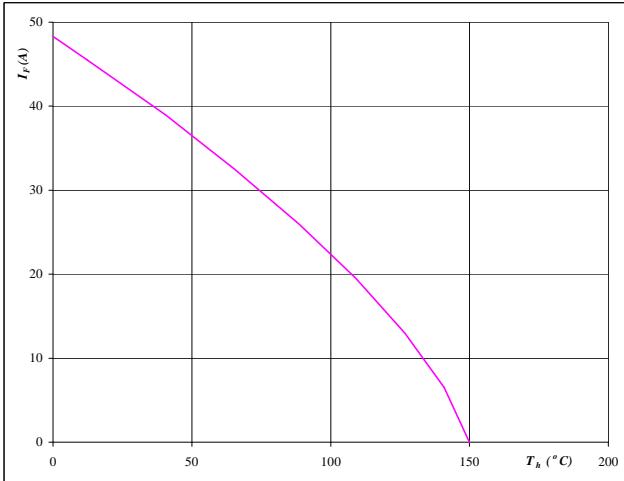
Figure 23
Power dissipation as a function of heatsink temperature
 $P_{\text{tot}} = f(T_h)$



At
 $T_j = 150$ °C

FWD

Figure 24
Forward current as a function of heatsink temperature
 $I_F = f(T_h)$



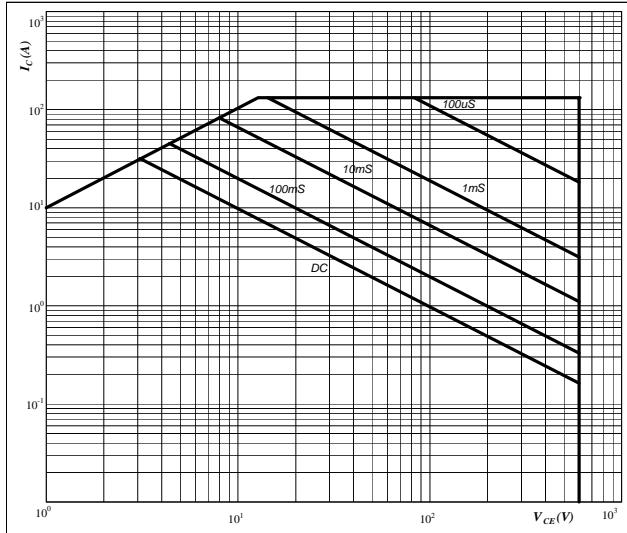
At
 $T_j = 150$ °C

FWD

Buck

Figure 25
**Safe operating area as a function
of collector-emitter voltage**

$$I_C = f(V_{CE})$$



At

D = single pulse

Th = 80 °C

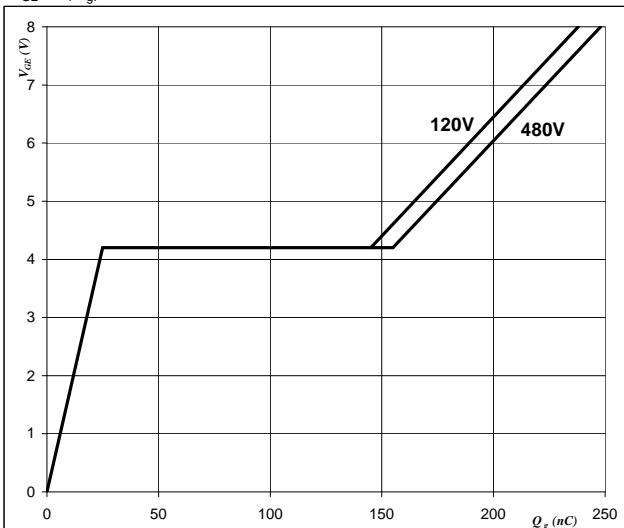
V_{GE} = 10 V

T_j = T_{jmax} °C

MOSFET

Figure 26
Gate voltage vs Gate charge

$$V_{GE} = f(Q_g)$$

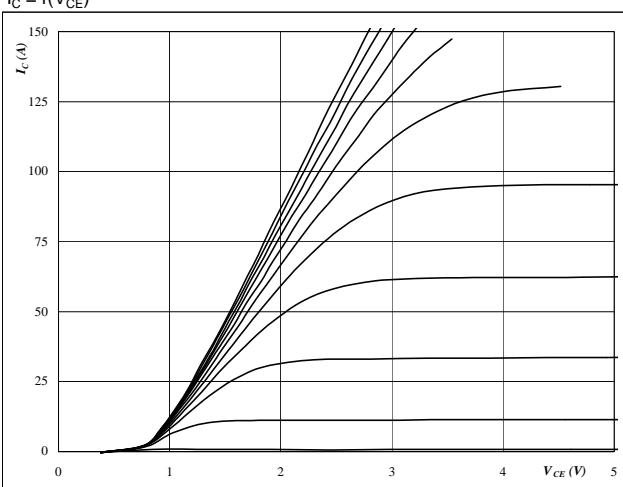


At

I_C = 15 A

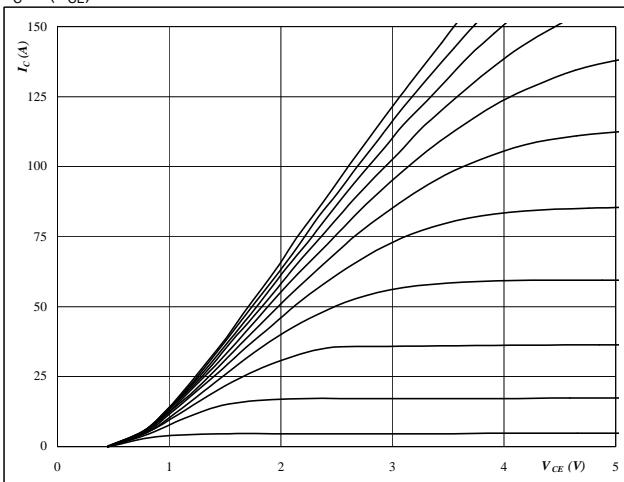
Polarity Switch IGBT

Figure 1
Typical output characteristics
 $I_C = f(V_{CE})$



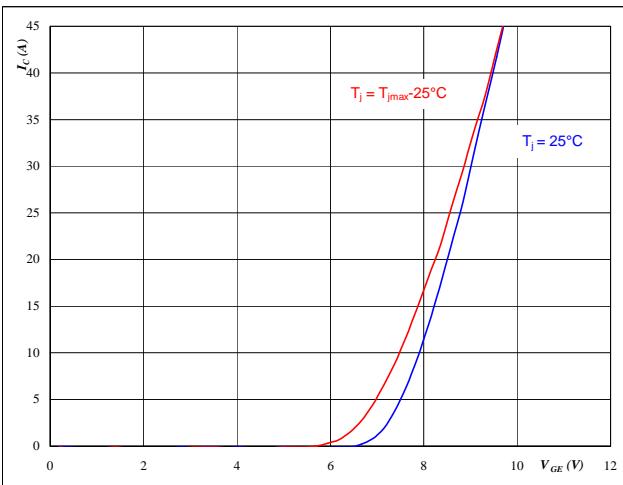
At
 $t_p = 250 \mu s$
 $T_j = 25 {}^\circ C$
 V_{GE} from 7 V to 17 V in steps of 1 V

Figure 2
Typical output characteristics
 $I_C = f(V_{CE})$



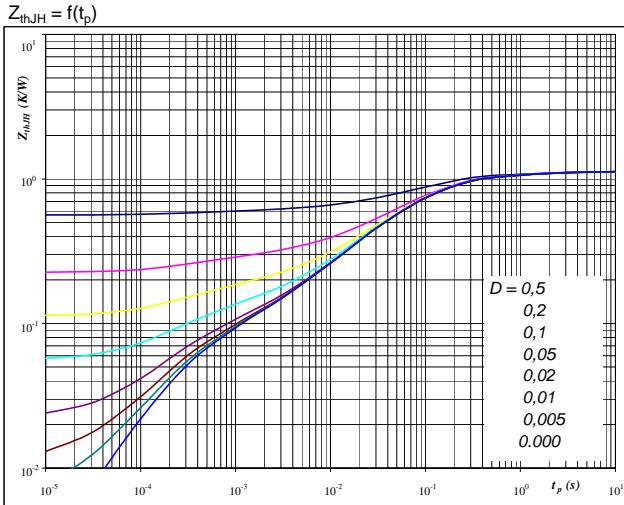
At
 $t_p = 250 \mu s$
 $T_j = 125 {}^\circ C$
 V_{GE} from 7 V to 17 V in steps of 1 V

Figure 3
Typical transfer characteristics
 $I_C = f(V_{GE})$



At
 $t_p = 250 \mu s$
 $V_{CE} = 10 V$

Figure 4
**IGBT transient thermal impedance
as a function of pulse width**
 $Z_{thJH} = f(t_p)$



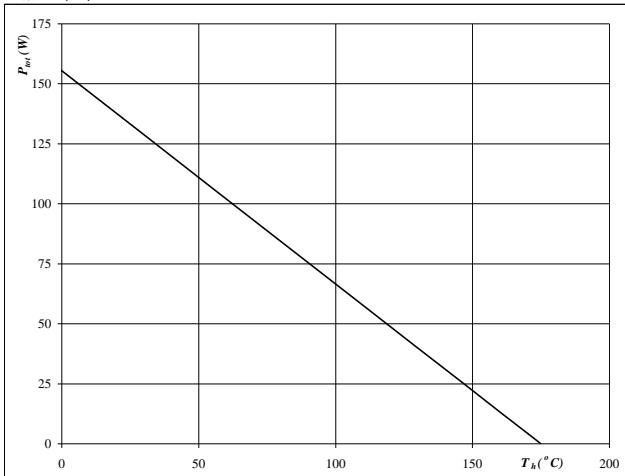
At
 $D = t_p / T$
 $R_{thJH} = 1,13 K/W$

Polarity Switch IGBT

Figure 5

Power dissipation as a function of heatsink temperature

$$P_{\text{tot}} = f(T_h)$$

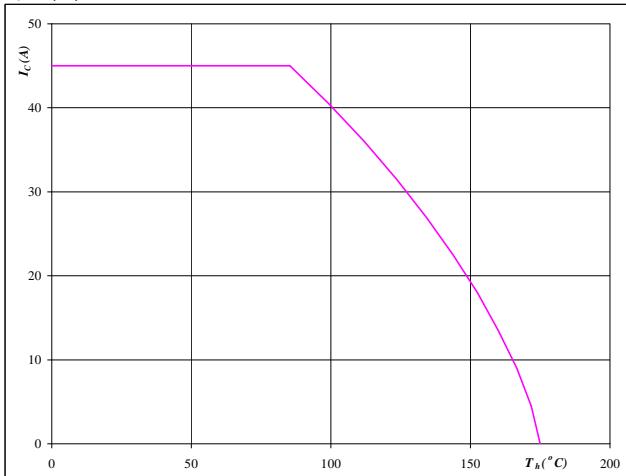

At

$$T_j = 175 \quad {}^\circ\text{C}$$

IGBT
Figure 6

Collector current as a function of heatsink temperature

$$I_C = f(T_h)$$


At

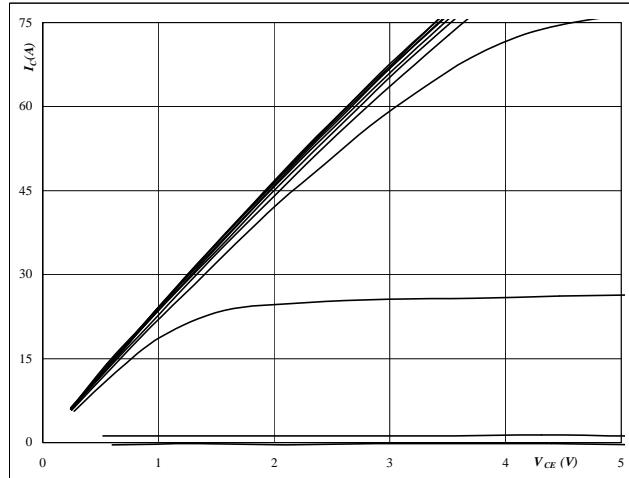
$$T_j = 175 \quad {}^\circ\text{C}$$

$$V_{GE} = 15 \quad \text{V}$$

INPUT BOOST

Figure 3
Typical output characteristics
 $I_D = f(V_{DS})$

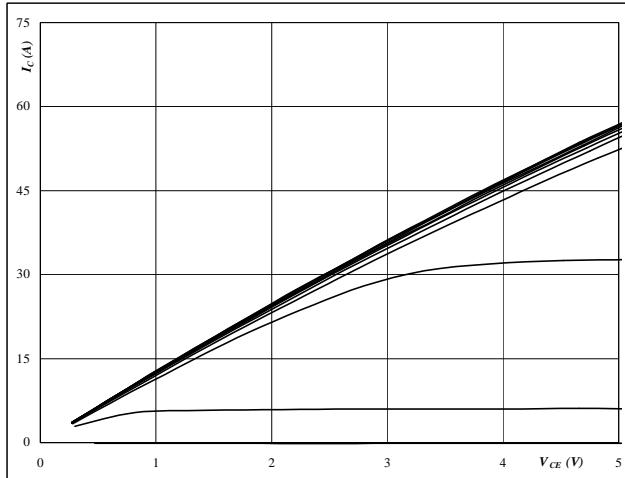
MOSFET



At
 $t_p = 250 \mu s$
 $T_j = 25 {}^\circ C$
 V_{GS} from 3 V to 13 V in steps of 1 V

Figure 4
Typical output characteristics
 $I_D = f(V_{DS})$

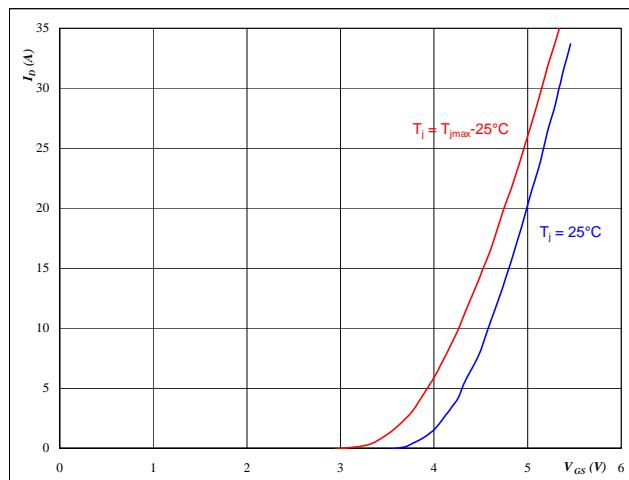
BOOST FWD



At
 $t_p = 250 \mu s$
 $T_j = 125 {}^\circ C$
 V_{GS} from 3 V to 13 V in steps of 1 V

Figure 3
Typical transfer characteristics
 $I_D = f(V_{DS})$

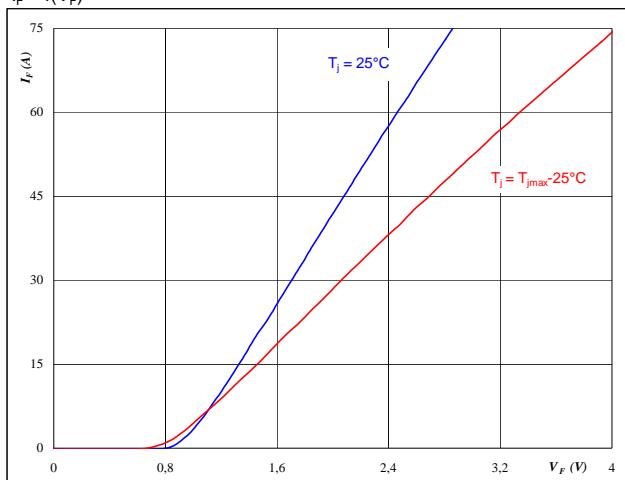
MOSFET



At
 $t_p = 250 \mu s$
 $V_{DS} = 10 V$

Figure 4
Typical diode forward current as a function of forward voltage
 $I_F = f(V_F)$

BOOST FWD

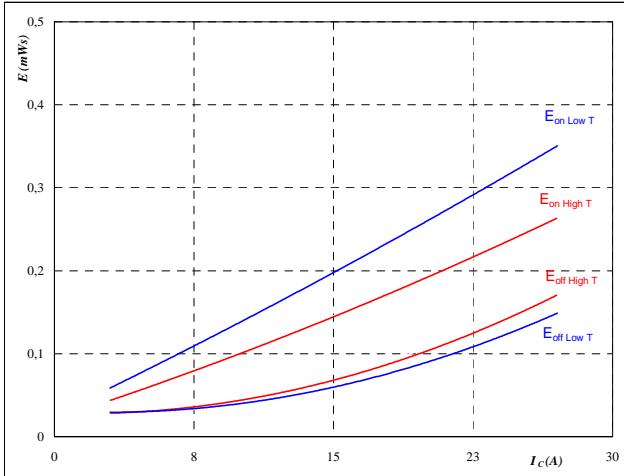


At
 $t_p = 250 \mu s$

INPUT BOOST

Figure 5
**Typical switching energy losses
as a function of collector current**

$$E = f(I_D)$$



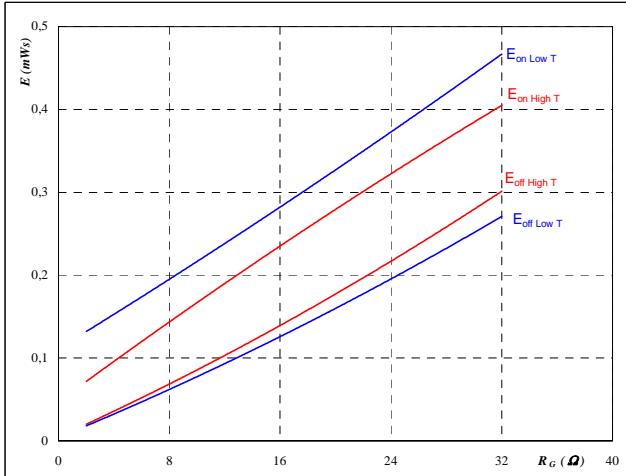
With an inductive load at

$$\begin{aligned} T_j &= 25/125 \quad ^\circ\text{C} \\ V_{DS} &= 400 \quad \text{V} \\ V_{GS} &= 10 \quad \text{V} \\ R_{gon} &= 8 \quad \Omega \\ R_{goff} &= 8 \quad \Omega \end{aligned}$$

MOSFET

Figure 6
**Typical switching energy losses
as a function of gate resistor**

$$E = f(R_G)$$

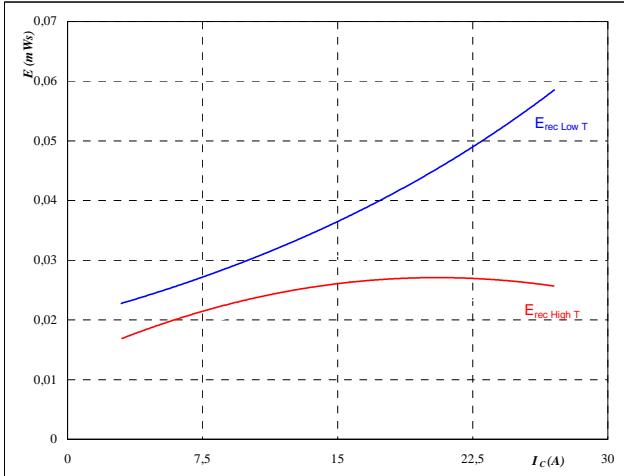


With an inductive load at

$$\begin{aligned} T_j &= 25/125 \quad ^\circ\text{C} \\ V_{DS} &= 400 \quad \text{V} \\ V_{GS} &= 10 \quad \text{V} \\ I_D &= 15 \quad \text{A} \end{aligned}$$

Figure 7
**Typical reverse recovery energy loss
as a function of collector (drain) current**

$$E_{rec} = f(I_c)$$



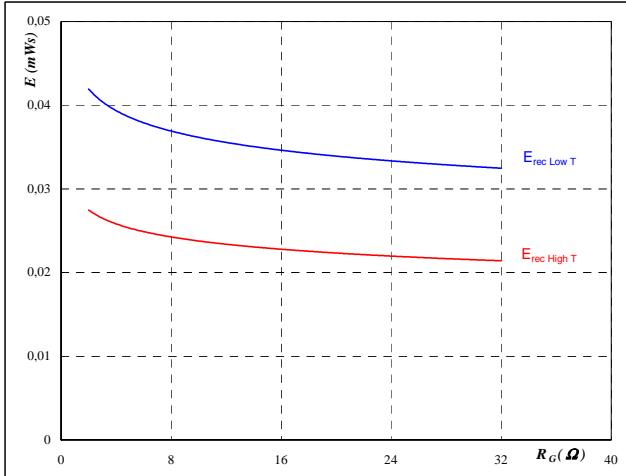
With an inductive load at

$$\begin{aligned} T_j &= 25/125 \quad ^\circ\text{C} \\ V_{DS} &= 400 \quad \text{V} \\ V_{GS} &= 10 \quad \text{V} \\ R_{gon} &= 8 \quad \Omega \\ R_{goff} &= 8 \quad \Omega \end{aligned}$$

MOSFET

Figure 8
**Typical reverse recovery energy loss
as a function of gate resistor**

$$E_{rec} = f(R_G)$$



With an inductive load at

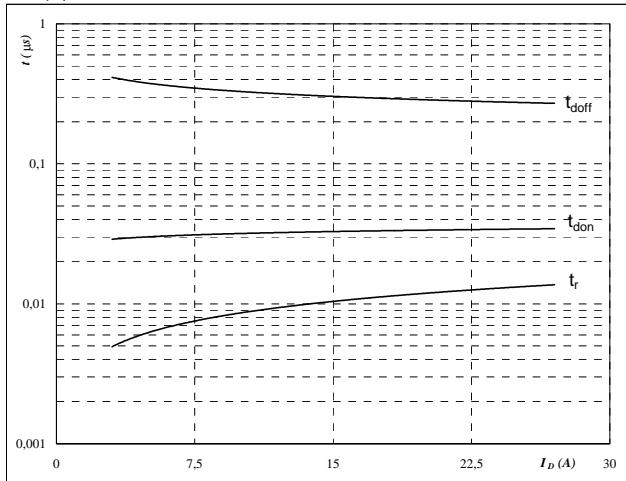
$$\begin{aligned} T_j &= 25/125 \quad ^\circ\text{C} \\ V_{DS} &= 400 \quad \text{V} \\ V_{GS} &= 10 \quad \text{V} \\ I_D &= 15 \quad \text{A} \end{aligned}$$

INPUT BOOST

Figure 9

Typical switching times as a function of collector current

$$t = f(I_D)$$



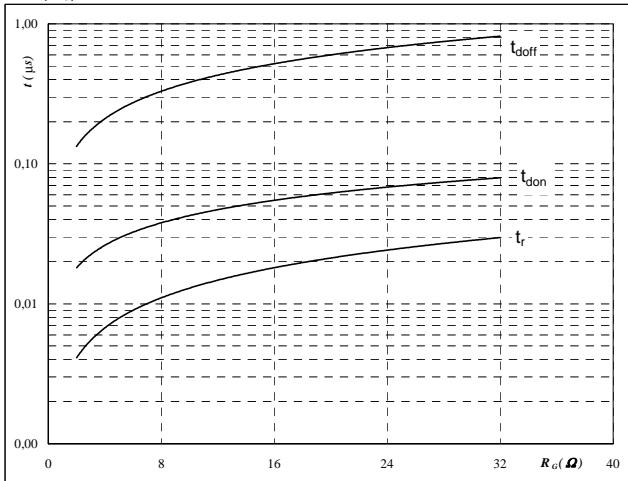
With an inductive load at

$T_j =$	125	°C
$V_{DS} =$	400	V
$V_{GS} =$	10	V
$R_{gon} =$	8	Ω
$R_{goff} =$	8	Ω

MOSFET
Figure 10

Typical switching times as a function of gate resistor

$$t = f(R_G)$$



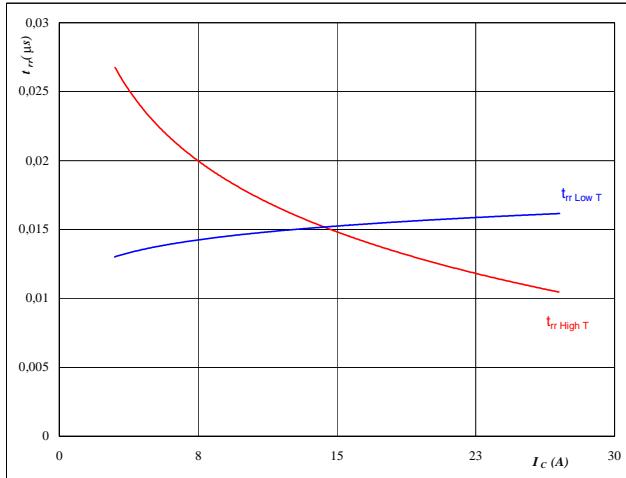
With an inductive load at

$T_j =$	125	°C
$V_{DS} =$	400	V
$V_{GS} =$	10	V
$I_C =$	15	A

Figure 11
BOOST FWD

Typical reverse recovery time as a function of collector current

$$t_{rr} = f(I_C)$$



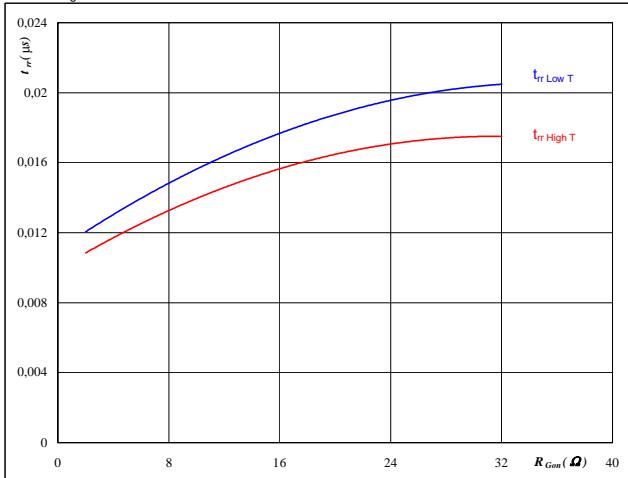
At

$T_j =$	25/125	°C
$V_{CE} =$	400	V
$V_{GE} =$	10	V
$R_{gon} =$	8	Ω

Figure 12
BOOST FWD

Typical reverse recovery time as a function of IGBT turn on gate resistor

$$t_{rr} = f(R_{Gon})$$



At

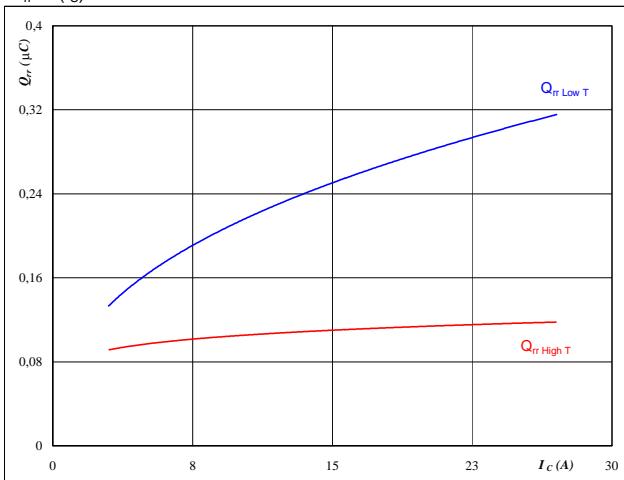
$T_j =$	25/125	°C
$V_R =$	400	V
$I_F =$	15	A
$V_{GS} =$	10	V

INPUT BOOST

Figure 13

Typical reverse recovery charge as a function of collector current

$$Q_{rr} = f(I_C)$$

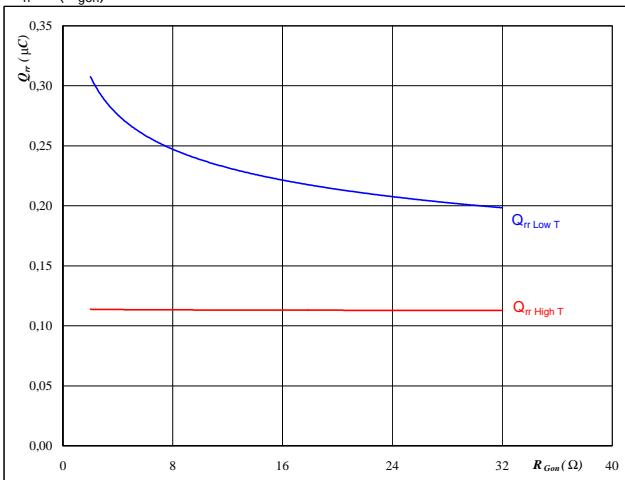

At

$$\begin{aligned} T_j &= 25/125 \quad ^\circ\text{C} \\ V_{CE} &= 400 \quad \text{V} \\ V_{GE} &= 10 \quad \text{V} \\ R_{gon} &= 8 \quad \Omega \end{aligned}$$

BOOST FWD
Figure 14

Typical reverse recovery charge as a function of IGBT turn on gate resistor

$$Q_{rr} = f(R_{gon})$$

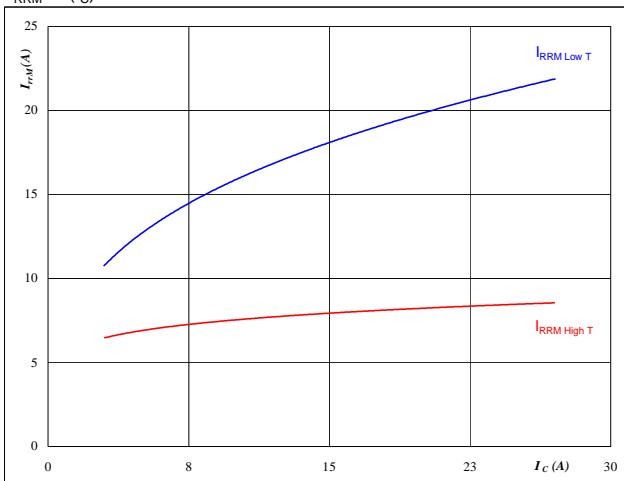

At

$$\begin{aligned} T_j &= 25/125 \quad ^\circ\text{C} \\ V_R &= 400 \quad \text{V} \\ I_F &= 15 \quad \text{A} \\ V_{GS} &= 10 \quad \text{V} \end{aligned}$$

Figure 15

Typical reverse recovery current as a function of collector current

$$I_{RRM} = f(I_C)$$

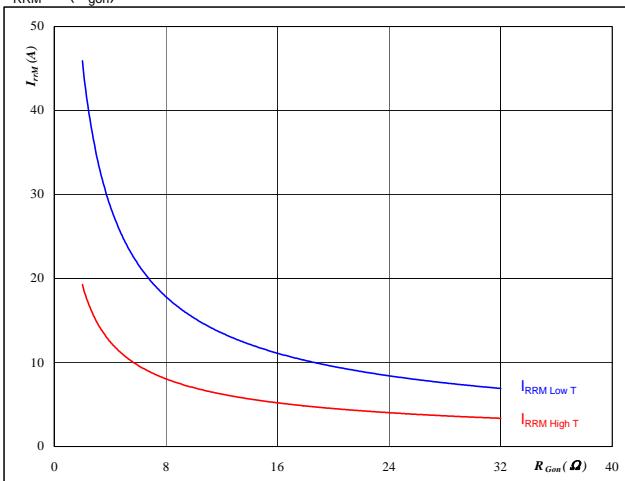

At

$$\begin{aligned} T_j &= 25/125 \quad ^\circ\text{C} \\ V_{CE} &= 400 \quad \text{V} \\ V_{GE} &= 10 \quad \text{V} \\ R_{gon} &= 8 \quad \Omega \end{aligned}$$

BOOST FWD
Figure 16

Typical reverse recovery current as a function of IGBT turn on gate resistor

$$I_{RRM} = f(R_{gon})$$

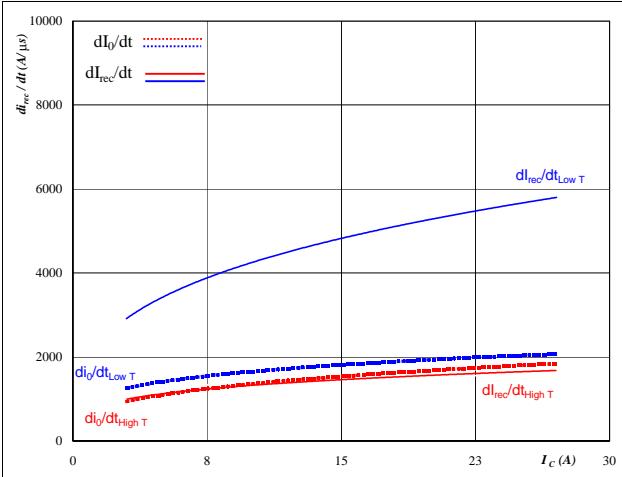

At

$$\begin{aligned} T_j &= 25/125 \quad ^\circ\text{C} \\ V_R &= 400 \quad \text{V} \\ I_F &= 15 \quad \text{A} \\ V_{GS} &= 10 \quad \text{V} \end{aligned}$$

INPUT BOOST

Figure 17

Typical rate of fall of forward
and reverse recovery current as a
function of collector current
 $dI_0/dt, dI_{rec}/dt = f(I_C)$

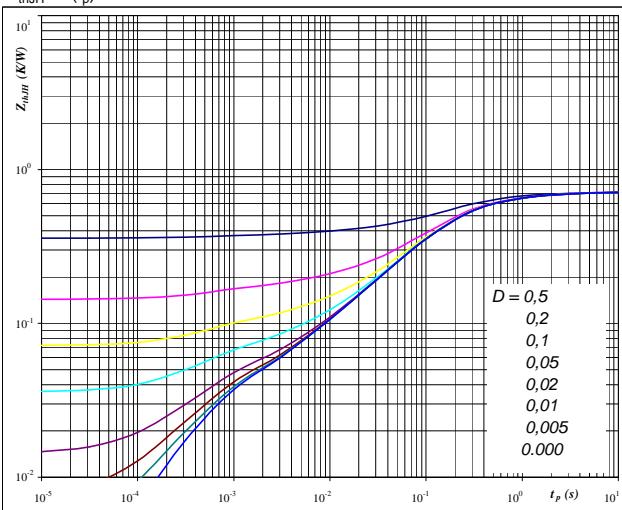

At

$T_j = 25/125 \text{ } ^\circ\text{C}$
 $V_{CE} = 400 \text{ V}$
 $V_{GE} = 10 \text{ V}$
 $R_{Gon} = 8 \Omega$

Figure 19

IGBT/MOSFET transient thermal impedance
as a function of pulse width

$$Z_{thJH} = f(t_p)$$


At

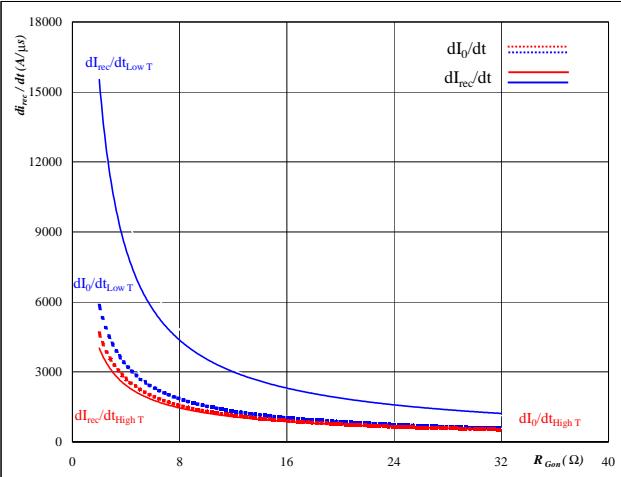
$D = t_p / T$
 $R_{thJH} = 0,72 \text{ K/W}$

IGBT thermal model values

R (C/W)	Tau (s)
0,01714	8,749
0,09725	1,33
0,3704	0,2014
0,1548	0,05998
0,04253	0,008246
0,03357	0,0005654

Figure 18

Typical rate of fall of forward
and reverse recovery current as a
function of IGBT turn on gate resistor
 $dI_0/dt, dI_{rec}/dt = f(R_{Gon})$

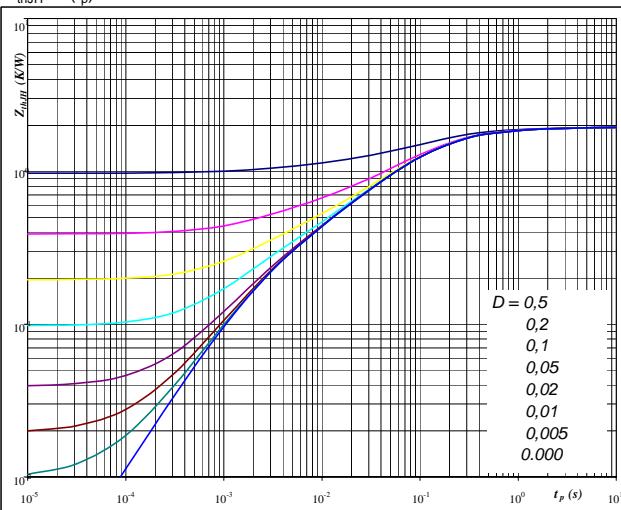

At

$T_j = 25/125 \text{ } ^\circ\text{C}$
 $V_R = 400 \text{ V}$
 $I_F = 15 \text{ A}$
 $V_{GS} = 10 \text{ V}$

Figure 20

FWD transient thermal impedance
as a function of pulse width

$$Z_{thJH} = f(t_p)$$


At

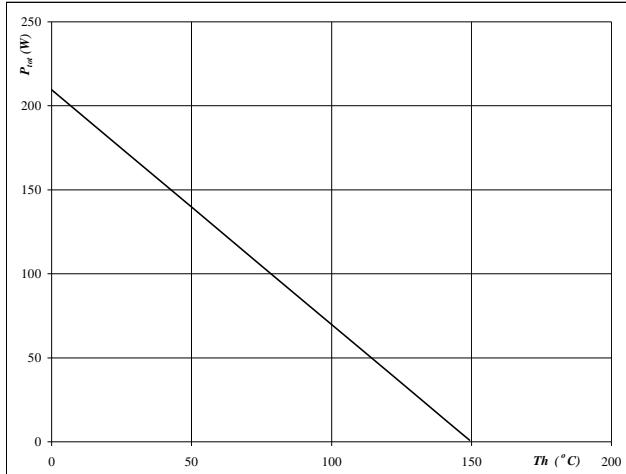
$D = t_p / T$
 $R_{thJH} = 1,95 \text{ K/W}$

FWD thermal model values

R (C/W)	Tau (s)
0,02765	9,595
0,1151	1,46
0,3598	0,3129
0,8406	0,09758
0,2989	0,02916
0,1886	0,007121

INPUT BOOST

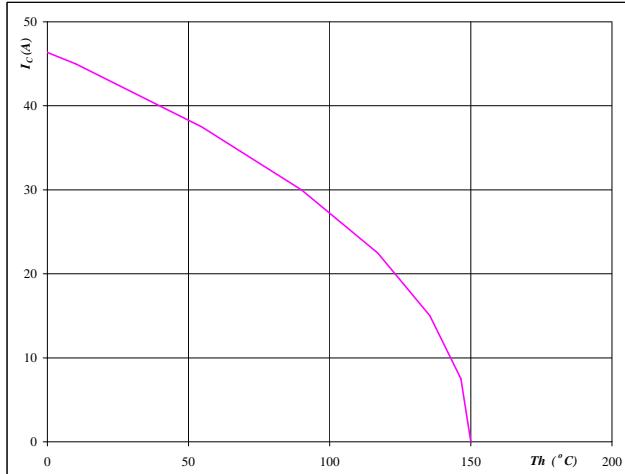
Figure 21
Power dissipation as a function of heatsink temperature
 $P_{\text{tot}} = f(T_h)$



At
T_j = 150 °C

MOSFET

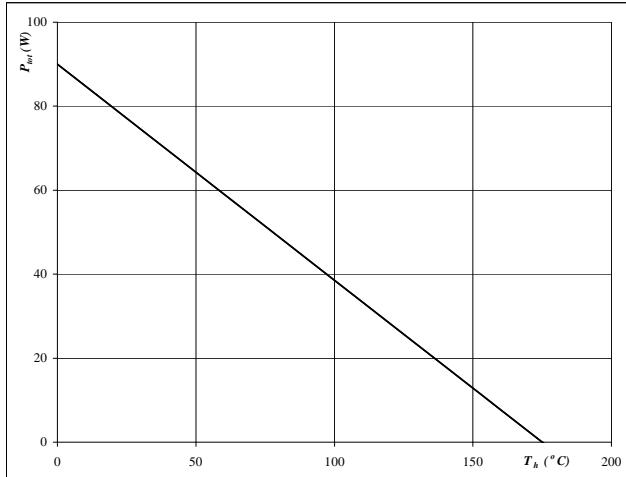
Figure 22
Collector/Drain current as a function of heatsink temperature
 $I_C = f(T_h)$



At
T_j = 150 °C
V_{GS} = 10 V

MOSFET

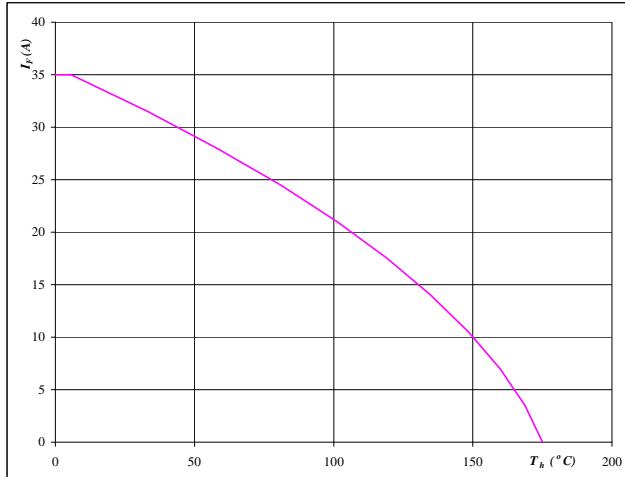
Figure 23
Power dissipation as a function of heatsink temperature
 $P_{\text{tot}} = f(T_h)$



At
T_j = 175 °C

BOOST FWD

Figure 24
Forward current as a function of heatsink temperature
 $I_F = f(T_h)$

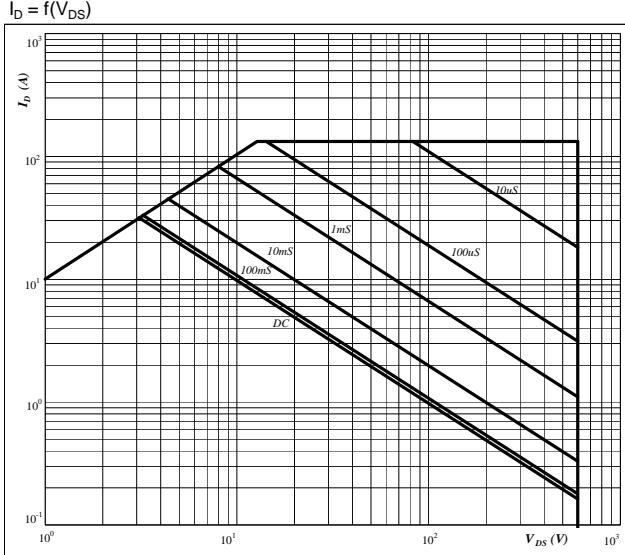


At
T_j = 175 °C

BOOST FWD

INPUT BOOST

Figure 25
**Safe operating area as a function
of drain-source voltage**

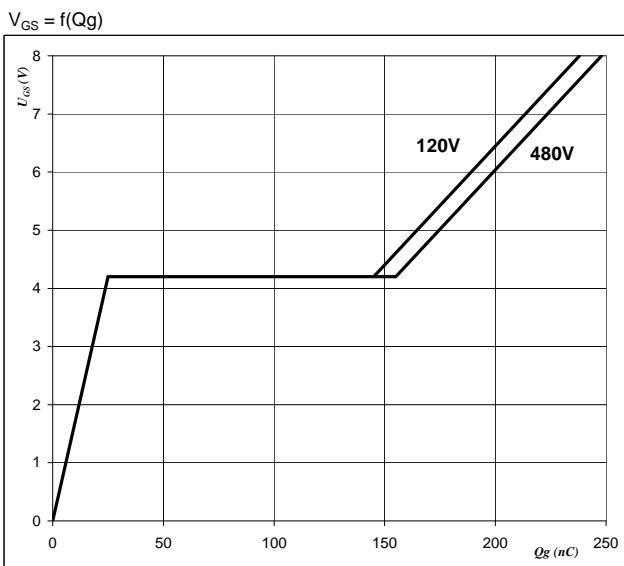


At

D = single pulse
 $T_h = 80 \text{ } ^\circ\text{C}$
 $V_{GS} = 10 \text{ V}$
 $T_j = T_{j\max} \text{ } ^\circ\text{C}$

MOSFET

Figure 26
Gate voltage vs Gate charge



At

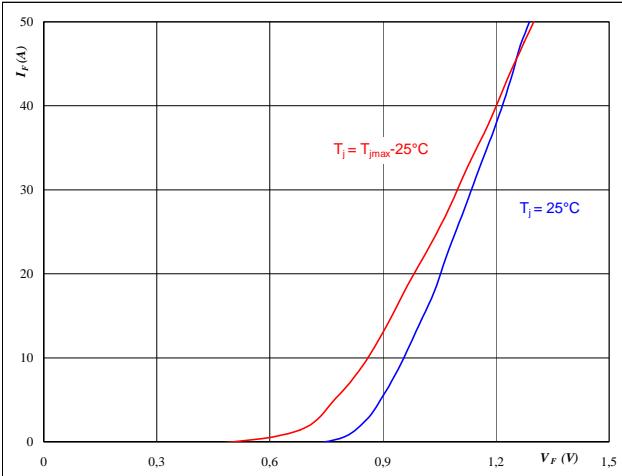
$I_D = 15 \text{ A}$

Bypass Diode

Figure 1

Typical diode forward current as a function of forward voltage

$$I_F = f(V_F)$$

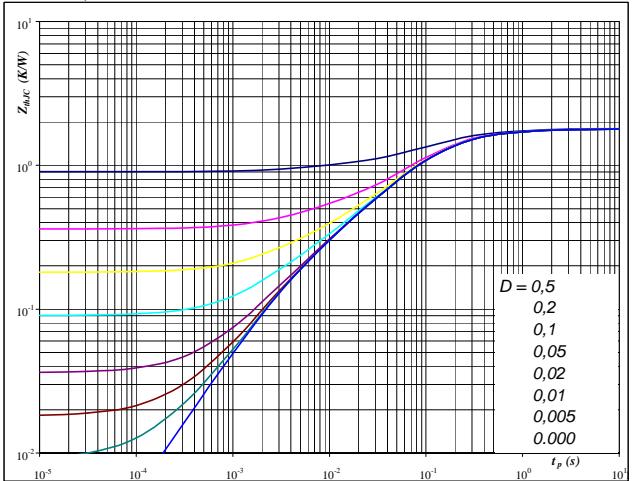

At

$$t_p = 250 \mu s$$

Bypass diode
Figure 2

Diode transient thermal impedance as a function of pulse width

$$Z_{thJH} = f(t_p)$$


At

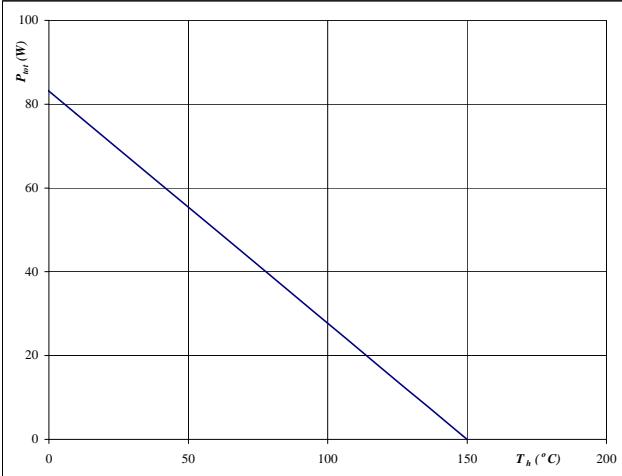
$$D = t_p / T$$

$$R_{thJH} = 1,804 \text{ K/W}$$

Figure 3

Power dissipation as a function of heatsink temperature

$$P_{tot} = f(T_h)$$

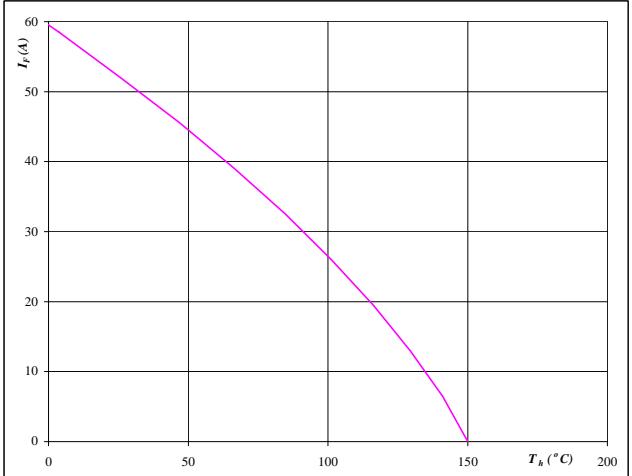

At

$$T_j = 150 {}^\circ C$$

Bypass diode
Figure 4

Forward current as a function of heatsink temperature

$$I_F = f(T_h)$$


At

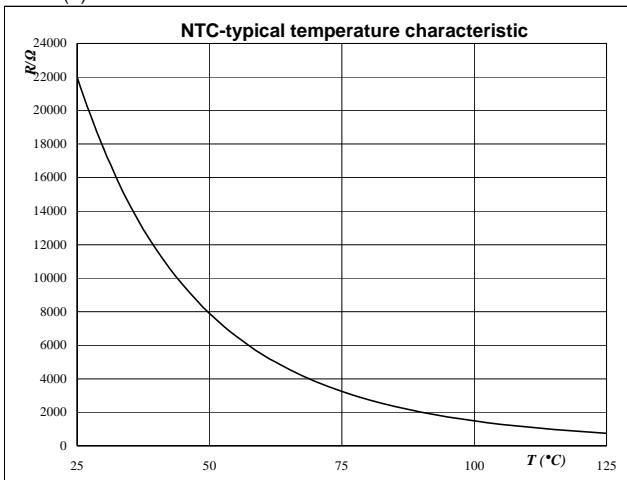
$$T_j = 150 {}^\circ C$$

Thermistor

Figure 1 Thermistor

Typical NTC characteristic
as a function of temperature

$$R_T = f(T)$$



Switching Definitions BUCK MOSFET

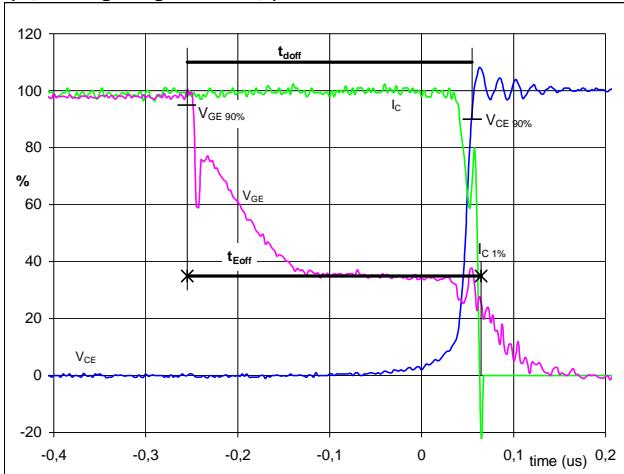
General conditions

T_j	= 125 °C
R_{gon}	= 8 Ω
R_{goff}	= 8 Ω

Figure 1

BUCK MOSFET

Turn-off Switching Waveforms & definition of t_{doff} , t_{Eoff}
 $(t_{Eoff} = \text{integrating time for } E_{off})$

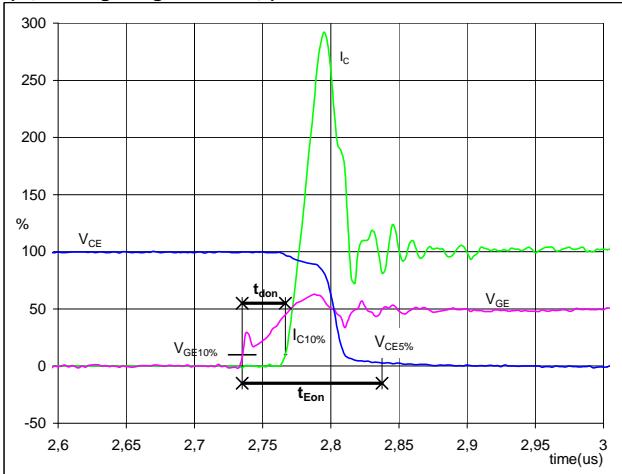


$V_{GE}(0\%) =$	0	V
$V_{GE}(100\%) =$	10	V
$V_C(100\%) =$	400	V
$I_C(100\%) =$	15	A
$t_{doff} =$	0,30	μs
$t_{Eoff} =$	0,32	μs

Figure 2

BUCK MOSFET

Turn-on Switching Waveforms & definition of t_{don} , t_{Eon}
 $(t_{Eon} = \text{integrating time for } E_{on})$

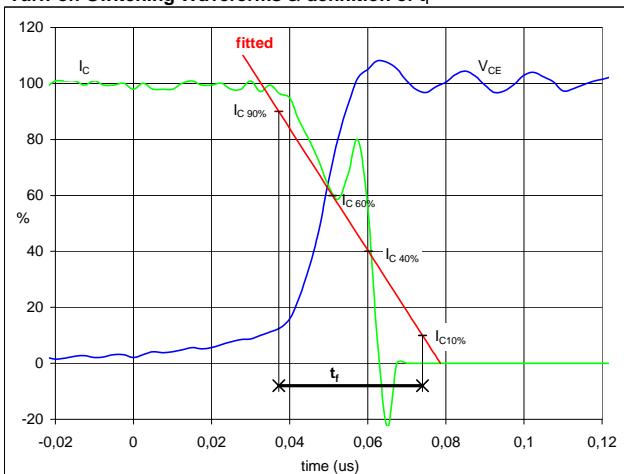


$V_{GE}(0\%) =$	0	V
$V_{GE}(100\%) =$	10	V
$V_C(100\%) =$	400	V
$I_C(100\%) =$	15	A
$t_{don} =$	0,03	μs
$t_{Eon} =$	0,10	μs

Figure 3

BUCK MOSFET

Turn-off Switching Waveforms & definition of t_f

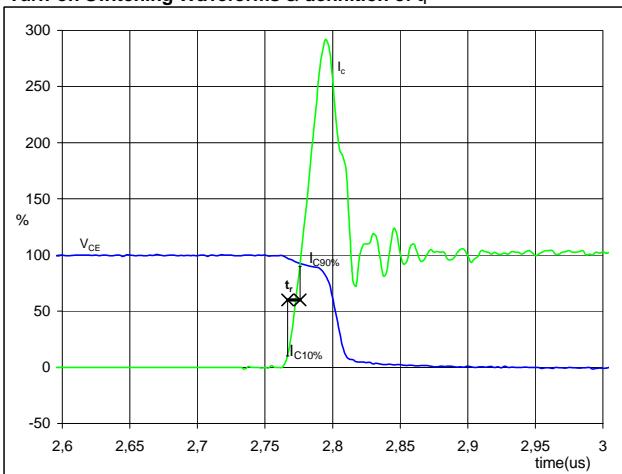


$V_C(100\%) =$	400	V
$I_C(100\%) =$	15	A
$t_f =$	0,004	μs

Figure 4

BUCK MOSFET

Turn-on Switching Waveforms & definition of t_r



$V_C(100\%) =$	400	V
$I_C(100\%) =$	15	A
$t_r =$	0,01	μs

Switching Definitions BUCK MOSFET

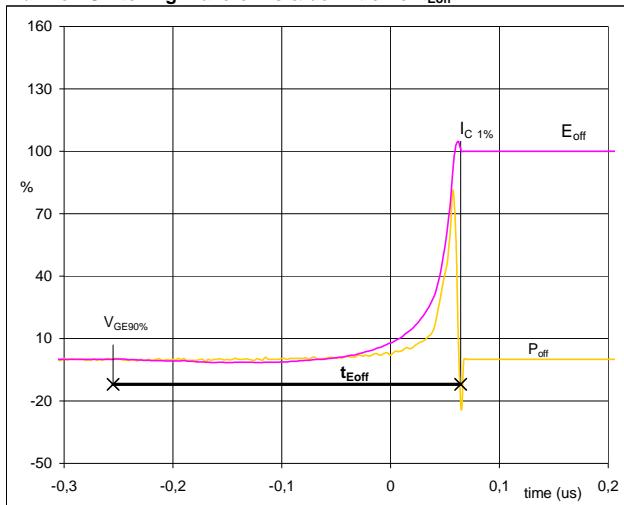
Figure 5
BUCK MOSFET
Turn-off Switching Waveforms & definition of t_{Eoff}

 P_{off} (100%) = 6,00 kW
 E_{off} (100%) = 0,08 mJ
 t_{Eoff} = 0,32 μs

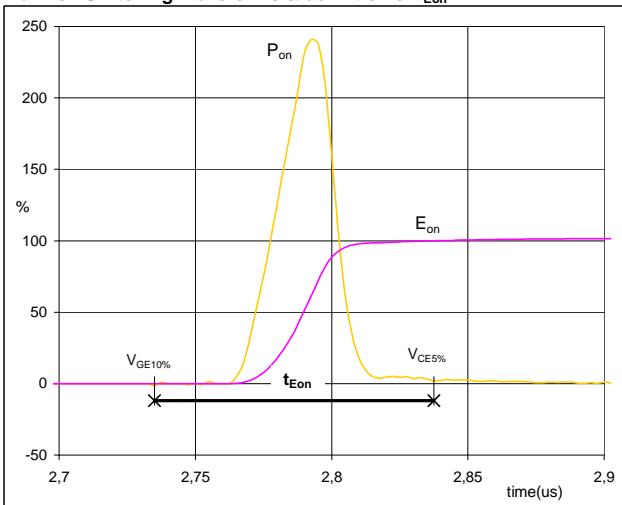
Figure 6
BUCK MOSFET
Turn-on Switching Waveforms & definition of t_{Eon}

 P_{on} (100%) = 6,00 kW
 E_{on} (100%) = 0,35 mJ
 t_{Eon} = 0,10 μs

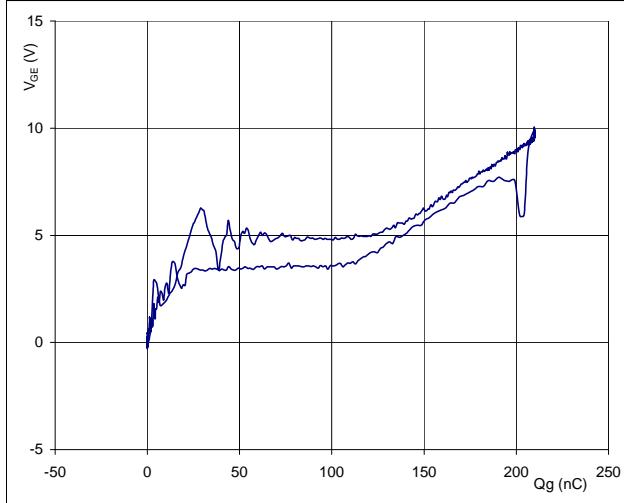
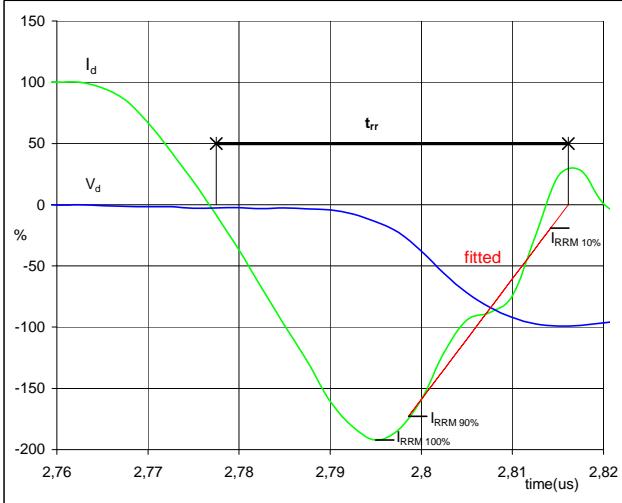
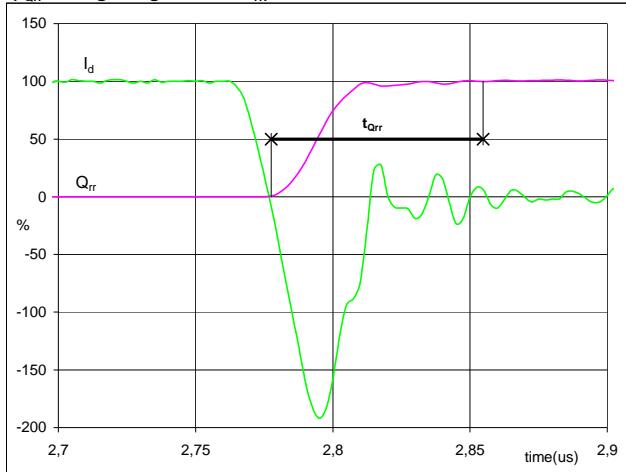
Figure 7
BUCK FWD
Gate voltage vs Gate charge (measured)

 V_{Geoff} = 0 V
 V_{Geon} = 10 V
 V_C (100%) = 400 V
 I_C (100%) = 15 A
 Q_g = 209,77 nC

Figure 8
BUCK MOSFET
Turn-off Switching Waveforms & definition of t_{rr}

 I_d (100%) = 15 A
 V_d (100%) = 400 V
 I_{RRM} (100%) = -29 A
 t_{rr} = 0,04 μs

Switching Definitions BUCK MOSFET

Figure 9
BUCK FWD

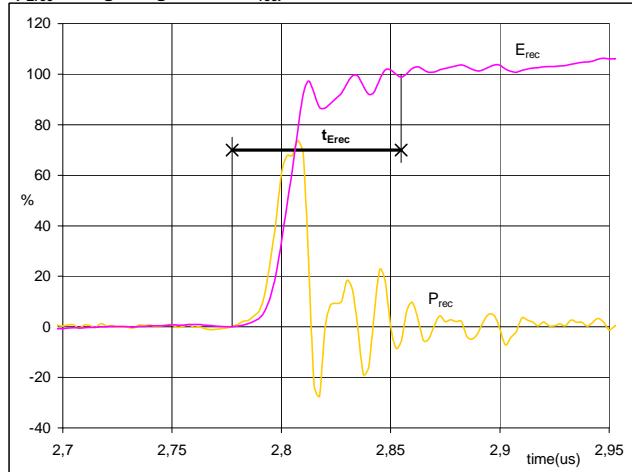
Turn-on Switching Waveforms & definition of t_{Qrr}
(t_{Qrr} = integrating time for Q_{rr})



$I_d(100\%) = 15 \text{ A}$
 $Q_{rr}(100\%) = 0,62 \mu\text{C}$
 $t_{Qrr} = 0,08 \mu\text{s}$

Figure 10
BUCK FWD

Turn-on Switching Waveforms & definition of t_{Erec}
(t_{Erec} = integrating time for E_{rec})



$P_{rec}(100\%) = 6,00 \text{ kW}$
 $E_{rec}(100\%) = 0,08 \text{ mJ}$
 $t_{Erec} = 0,08 \mu\text{s}$

Switching Definitions INP. BOOST

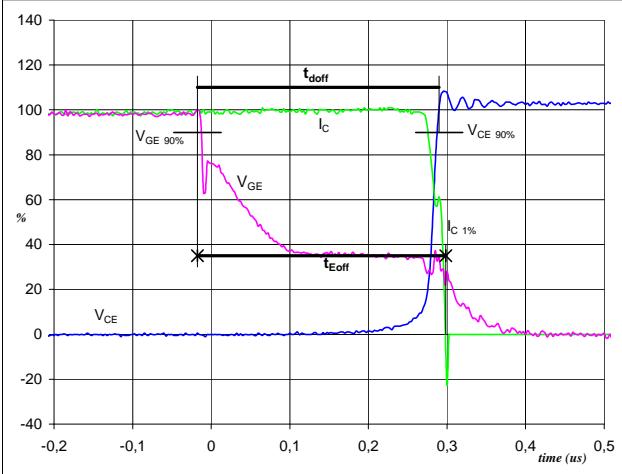
General conditions

T_j	= 125 °C
R_{gon}	= 8 Ω
R_{goff}	= 8 Ω

Figure 1

MOSFET

Turn-off Switching Waveforms & definition of t_{doff} , t_{Eoff}
(t_{Eoff} = integrating time for E_{off})



$V_{GE}(0\%) = 0 \text{ V}$

$V_{GE}(100\%) = 10 \text{ V}$

$V_C(100\%) = 400 \text{ V}$

$I_C(100\%) = 15 \text{ A}$

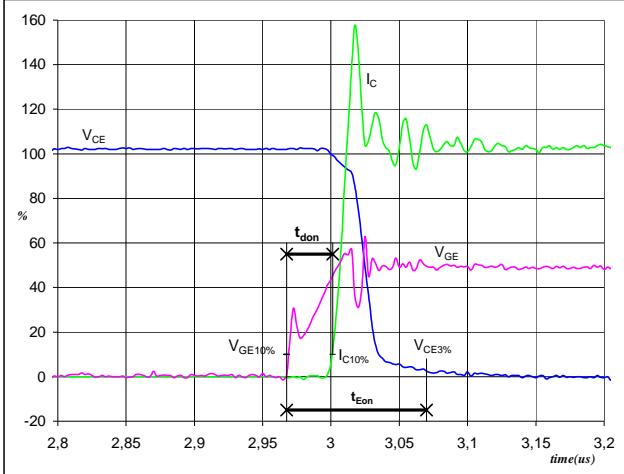
$t_{doff} = 0,30 \mu\text{s}$

$t_{Eoff} = 0,32 \mu\text{s}$

Figure 2

MOSFET

Turn-on Switching Waveforms & definition of t_{don} , t_{Eon}
(t_{Eon} = integrating time for E_{on})



$V_{GE}(0\%) = 0 \text{ V}$

$V_{GE}(100\%) = 10 \text{ V}$

$V_C(100\%) = 400 \text{ V}$

$I_C(100\%) = 15 \text{ A}$

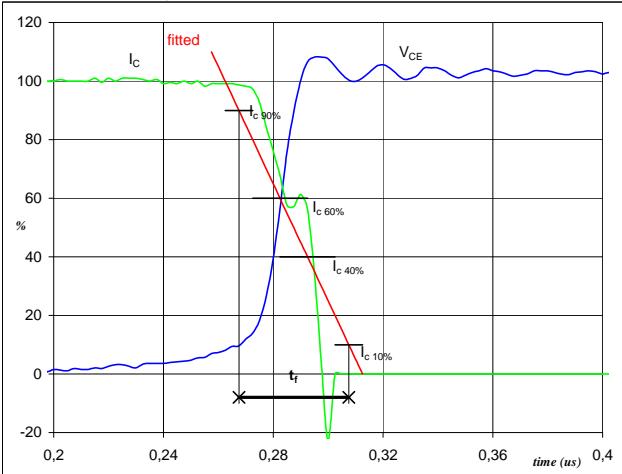
$t_{don} = 0,04 \mu\text{s}$

$t_{Eon} = 0,10 \mu\text{s}$

Figure 3

MOSFET

Turn-off Switching Waveforms & definition of t_f



$V_C(100\%) = 400 \text{ V}$

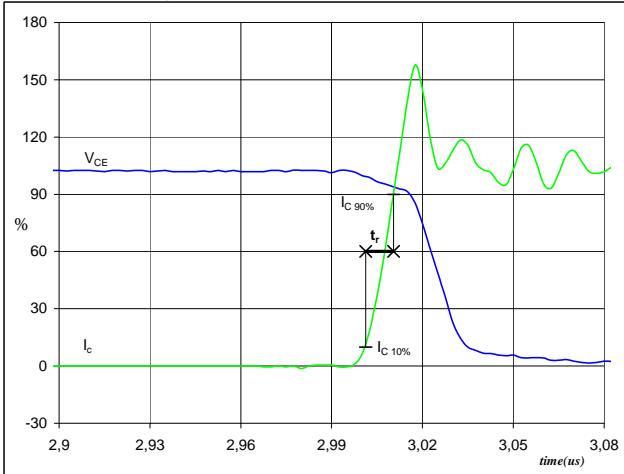
$I_C(100\%) = 15 \text{ A}$

$t_f = 0,03 \mu\text{s}$

Figure 4

MOSFET

Turn-on Switching Waveforms & definition of t_r

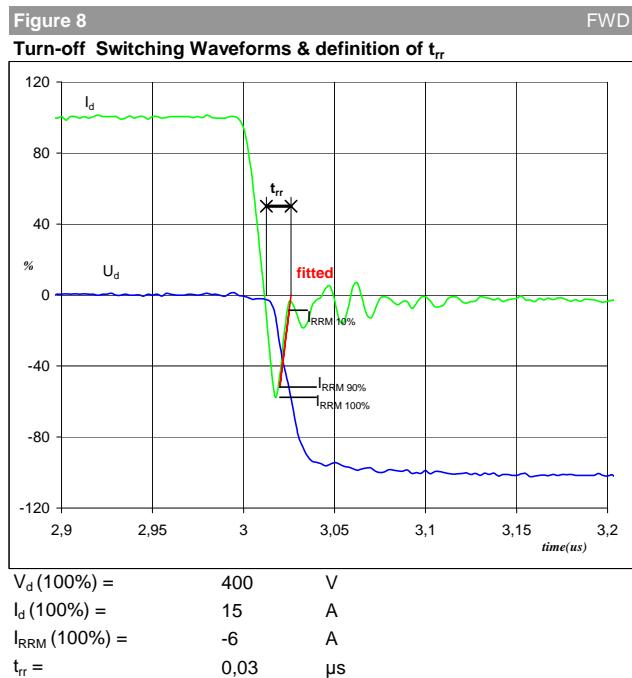
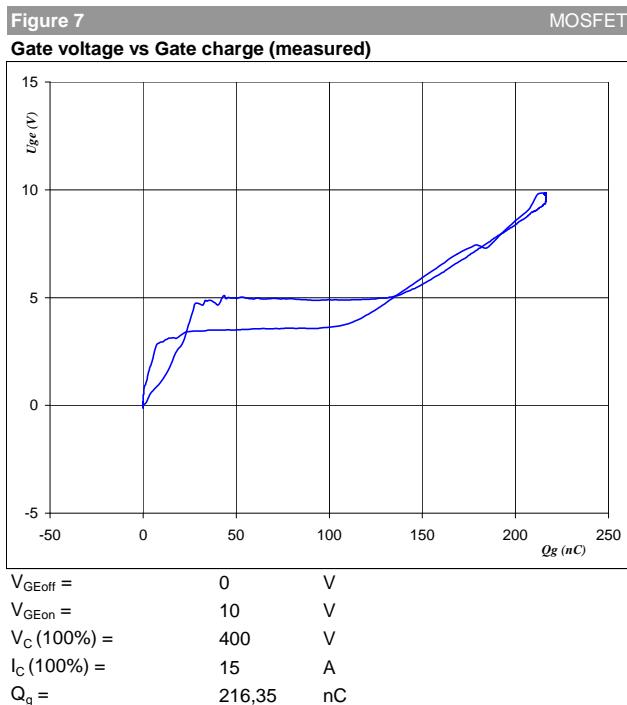
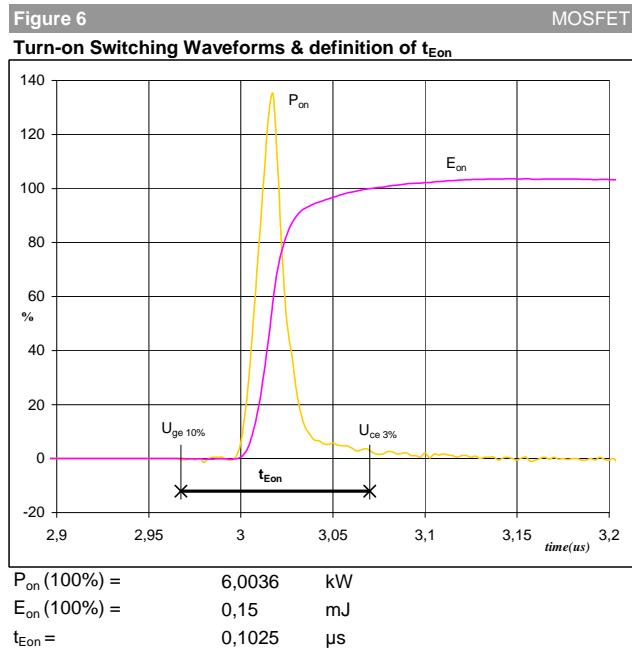
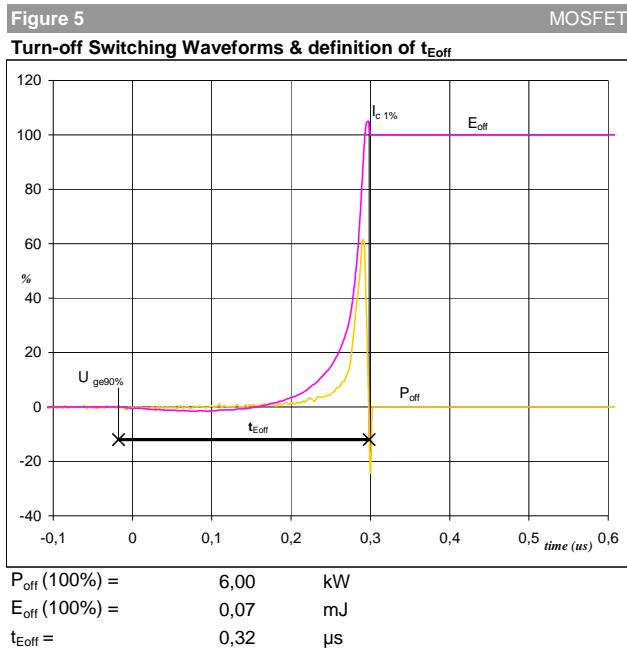


$V_C(100\%) = 400 \text{ V}$

$I_C(100\%) = 15 \text{ A}$

$t_r = 0,01 \mu\text{s}$

Switching Definitions INP. BOOST

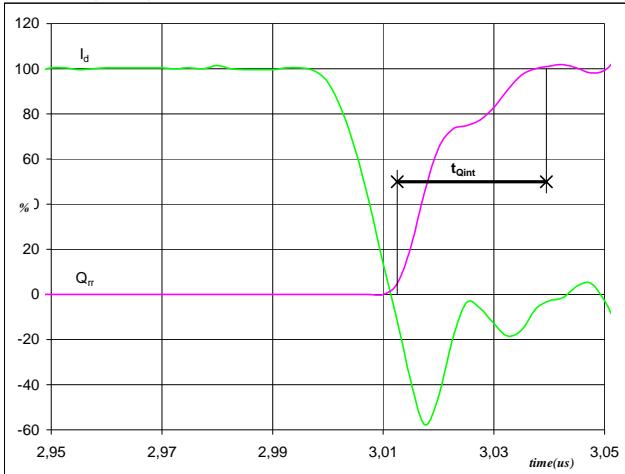


Switching Definitions INP. BOOST

Figure 9

FWD

Turn-on Switching Waveforms & definition of t_{Qrr}
(t_{Qrr} = integrating time for Q_{rr})

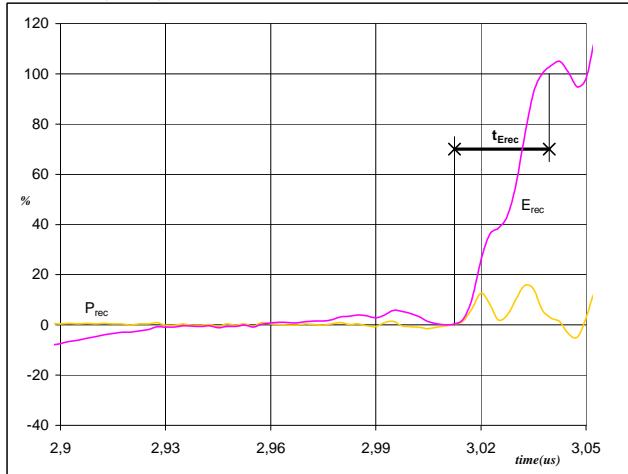


$I_d(100\%) = 15 \text{ A}$
 $Q_{rr}(100\%) = 0,19 \mu\text{C}$
 $t_{Qint} = 0,03 \mu\text{s}$

Figure 10

FWD

Turn-on Switching Waveforms & definition of t_{Erec}
(t_{Erec} = integrating time for E_{rec})



$P_{rec}(100\%) = 6,00 \text{ kW}$
 $E_{rec}(100\%) = 0,06 \text{ mJ}$
 $t_{Erec} = 0,03 \mu\text{s}$

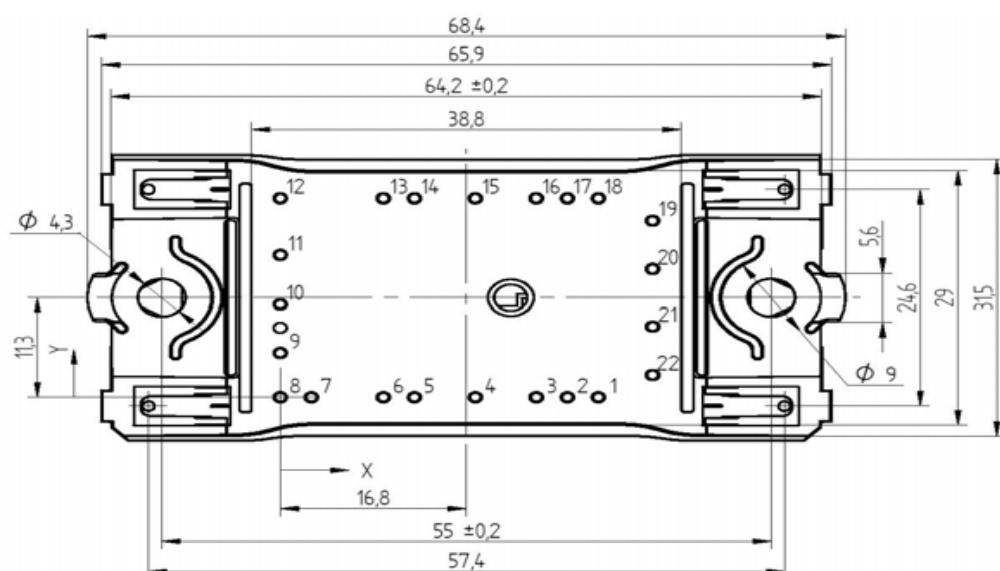
Ordering Code and Marking - Outline - Pinout

Ordering Code & Marking

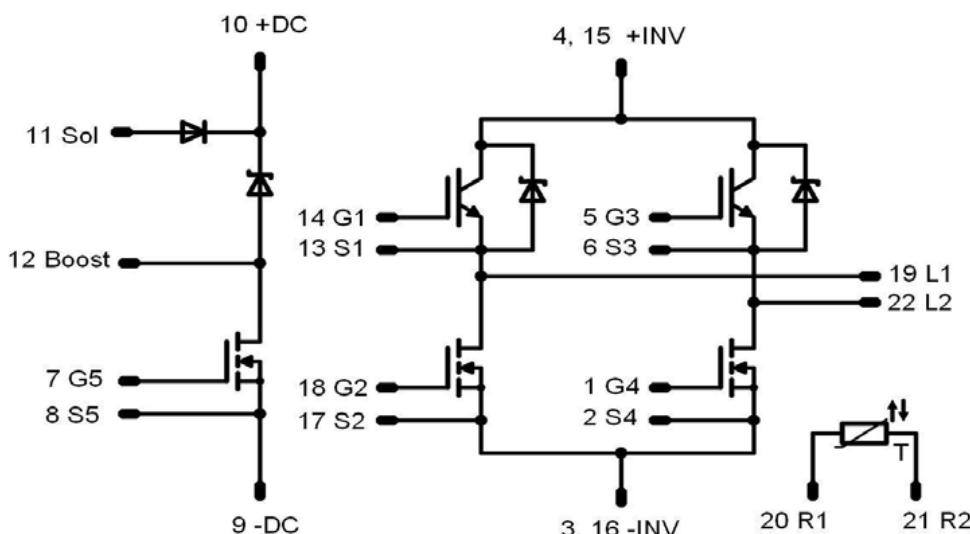
Version	Ordering Code	in DataMatrix as	in packaging barcode as
without thermal paste 12mm housing	10-FZ06BIA041FS01-P898E10	P898E10	P898E10

Outline

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1	28,7	0
2	25,9	0
3	23,1	0
4	17,6	0
5	12,1	0
6	9,3	0
7	2,8	0
8	0	0
9	0	5,05
10	0	10,55
11	0	16,15
12	0	22,6
13	9,3	22,6
14	12,1	22,6
15	17,6	22,6
16	23,1	22,6
17	25,9	22,6
18	28,7	22,6
19	33,6	20,05
20	33,6	14,55
21	33,6	8,05
22	33,6	2,55



Pinout



PRODUCT STATUS DEFINITIONS

Datasheet Status	Product Status	Definition
Target	Formative or In Design	This datasheet contains the design specifications for product development. Specifications may change in any manner without notice. The data contained is exclusively intended for technically trained staff.
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